

RL78/G12

**RENESAS MCU** 

R01DS0193EJ0220 Rev.2.20 Oct 31, 2018

True Low Power Platform (as low as 63  $\mu$ A/MHz), 1.8V to 5.5V operation, 2 to 16 Kbyte Flash, 31 DMIPS at 24MHz, for General Purpose Applications

#### 1. OUTLINE

#### 1.1 Features

#### Ultra-low power consumption technology

- VDD = single power supply voltage of 1.8 to 5.5 V which can operate at a low voltage
- HALT mode
- STOP mode
- SNOOZE mode

#### **RL78 CPU core**

- CISC architecture with 3-stage pipeline
- Minimum instruction execution time: Can be changed from high speed (0.04167 μs: @ 24 MHz operation with high-speed on-chip oscillator) to ultra-low speed (1 μs: @ 1 MHz operation)
- Address space: 1 MB
- General-purpose registers: (8-bit register x 8) x 4 banks
- On-chip RAM: 256 B to 2 KB

#### Code flash memory

- Code flash memory: 2 to 16 KB
- Block size: 1 KB
- Prohibition of block erase and rewriting (security function)
- · On-chip debug function
- Self-programming (with flash shield window function)

# Data flash memory Note

- · Data flash memory: 2 KB
- Back ground operation (BGO): Instructions are executed from the program memory while rewriting the data flash memory.
- Number of rewrites: 1,000,000 times (TYP.)
- Voltage of rewrites: VDD = 1.8 to 5.5 V

# High-speed on-chip oscillator

- Select from 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz, and 1 MHz
- High accuracy: +/- 1.0 % (VDD = 1.8 to 5.5 V, TA = -20 to +85 °C)

### Operating ambient temperature

- T<sub>A</sub> = -40 to +85 °C (A: Consumer applications, D: Industrial applications)
- T<sub>A</sub> = -40 to +105 °C (G: Industrial applications) Note

#### Power management and reset function

- On-chip power-on-reset (POR) circuit
- On-chip voltage detector (LVD) (Select interrupt and reset from 12 levels)

# DMA (Direct Memory Access) controller Note

- 2 channels
- Number of clocks during transfer between 8/16-bit SFR and internal RAM: 2 clocks

# Multiplier and divider/multiply-accumulator

- 16 bits x 16 bits = 32 bits (Unsigned or signed)
- 32 bits x 32 bits = 32 bits (Unsigned)
- 16 bits x 16 bits + 32 bits = 32 bits (Unsigned or signed)

#### Serial interface

CSI : 1 to 3 channels
 UART : 1 to 3 channels
 Simplified I<sup>2</sup>C communication : 0 to 3 channels
 I<sup>2</sup>C communication : 1 channel

#### **Timer**

16-bit timer : 4 to 8 channels12-bit interval timer : 1 channel

Watchdog timer : 1 channel (operable with the dedicated low-speed on-chip

oscillator)

### A/D converter

- 8/10-bit resolution A/D converter (VDD = 1.8 to 5.5 V)
- 8 to 11 channels, internal reference voltage (1.45 V), and temperature sensor Note

#### I/O port

- I/O port: 18 to 26
   (N-ch open drain I/O [withstand voltage of 6 V]: 2,
   N-ch open drain I/O [VDD withstand voltage]: 4 to 9)
- Can be set to N-ch open drain, TTL input buffer, and on-chip pull-up resistor
- Different potential interface: Can connect to a 1.8/2.5/3 V device
- On-chip key interrupt function
- · On-chip clock output/buzzer output controller

#### **Others**

• On-chip BCD (binary-coded decimal) correction circuit

**Note** Can be selected only in HS (high-speed main) mode.

Remark The functions mounted depend on the product.

See 1.7 Outline of Functions.

O ROM, RAM capacities

Code flash	Data flash	RAM	20 pins	24 pins	30 pins
16 KB	2 KB	2 KB	_	_	R5F102AA
	_		_	_	R5F103AA
	2 KB	1.5 KB	R5F1026A Note 1	R5F1027A Note 1	_
	_		R5F1036A Note 1	R5F1037A Note 1	_
12 KB	2KB	1 KB	R5F10269 Note 1	R5F10279 Note 1	R5F102A9
	_		R5F10369 Note 1	R5F10379 Note 1	R5F103A9
8 KB	2 KB	768 B	R5F10268 Note 1	R5F10278 Note 1	R5F102A8
	_		R5F10368 Note 1	R5F10378 Note 1	R5F103A8
4 KB	2KB	512 B	R5F10267	R5F10277	R5F102A7
	_		R5F10367	R5F10377	R5F103A7
2 KB	2 KB	256 B	R5F10266 Note 2	_	_
	_		R5F10366 Note 2	_	_

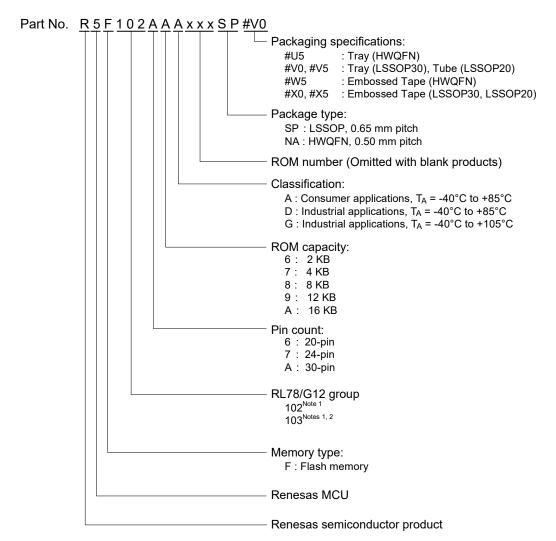
Notes 1. This is 640 bytes when the self-programming function or data flash function is used. (For details, see CHAPTER 3 CPU ARCHITECTURE in the RL78/G12 User's Manual.)

2. The self-programming function cannot be used for R5F10266 and R5F10366.

Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.

#### 1.2 List of Part Numbers

Figure 1-1. Part Number, Memory Size, and Package of RL78/G12



- Notes 1. For details about the differences between the R5F102 products and the R5F103 products of RL78/G12, see 1.1 Differences between the R5F102 Products and the R5F103 Products.
  - 2. Products only for "A: Consumer applications ( $T_A = -40 \text{ to } +85^{\circ}\text{C}$ )" and "D: Industrial applications ( $T_A = -40 \text{ to } +85^{\circ}\text{C}$ )"

Table 1-1. List of Ordering Part Numbers

Pin count	Package	Data flash	Fields of Application Note	Part Number
20 pins	20-pin plastic LSSOP (4.4 × 6.5 mm, 0.65 mm pitch)  Not result of the property	Mounted	А	R5F1026AASP#V5, R5F10269ASP#V5, R5F10268ASP#V5, R5F10267ASP#V5, R5F10266ASP#V5 R5F1026AASP#X5, R5F10269ASP#X5, R5F10268ASP#X5, R5F10267ASP#X5, R5F10266ASP#X5
			D	R5F1026ADSP#V5, R5F10269DSP#V5, R5F10268DSP#V5, R5F10267DSP#V5, R5F10266DSP#V5 R5F1026ADSP#X5, R5F10269DSP#X5, R5F10268DSP#X5, R5F10267DSP#X5, R5F10266DSP#X5
			G	R5F1026AGSP#V5, R5F10269GSP#V5, R5F10268GSP#V5, R5F10267GSP#V5, R5F10266GSP#V5 R5F1026AGSP#X5, R5F10269GSP#X5, R5F10268GSP#X5, R5F10267GSP#X5, R5F10266GSP#X5
		Not mounted	A	R5F1036AASP#V5, R5F10369ASP#V5, R5F10368ASP#V5, R5F10367ASP#V5, R5F10366ASP#V5 R5F1036AASP#X5, R5F10369ASP#X5, R5F10368ASP#X5, R5F10367ASP#X5, R5F10366ASP#X5
			D	R5F1036ADSP#V5, R5F10369DSP#V5, R5F10368DSP#V5, R5F10367DSP#V5, R5F10366DSP#V5 R5F1036ADSP#X5, R5F10369DSP#X5, R5F10368DSP#X5, R5F10367DSP#X5, R5F10366DSP#X5
24 pins	oins HWQFN	VQFN × 4 mm, 0.5		R5F1027AANA#U5, R5F10279ANA#U5, R5F10278ANA#U5, R5F10277ANA#U5 R5F1027AANA#W5, R5F10279ANA#W5, R5F10278ANA#W5, R5F10277ANA#W5
	mm pitch)		D	R5F1027ADNA#U5, R5F10279DNA#U5, R5F10278DNA#U5, R5F10277DNA#U5 R5F1027ADNA#W5, R5F10279DNA#W5, R5F10278DNA#W5, R5F10277DNA#W5
			G	R5F1027AGNA#U5, R5F10279GNA#U5, R5F10278GNA#U5, R5F10277GNA#U5 R5F1027AGNA#W5, R5F10279GNA#W5, R5F10278GNA#W5, R5F10277GNA#W5
		Not mounted	А	R5F1037AANA#U5, R5F10379ANA#U5, R5F10377ANA#U5, R5F10377ANA#U5, R5F1037AANA#W5, R5F10379ANA#W5, R5F10378ANA#W5, R5F10378ANA#W5
			D	R5F1037ADNA#U5, R5F10379DNA#U5, R5F10378DNA#U5, R5F10377DNA#U5, R5F1037ADNA#W5, R5F10379DNA#W5, R5F10378DNA#W5, R5F10377DNA#W5
30 pins		Mounted	Α	R5F102AAASP#V0, R5F102A9ASP#V0, R5F102A8ASP#V0, R5F102A7ASP#V0 R5F102AAASP#X0, R5F102A9ASP#X0, R5F102A8ASP#X0, R5F102A7ASP#X0
	(300), 0.65 mm		D	R5F102AADSP#V0, R5F102A9DSP#V0, R5F102A8DSP#V0, R5F102A7DSP#V0 R5F102AADSP#X0, R5F102A9DSP#X0, R5F102A8DSP#X0, R5F102A7DSP#X0
	pitcn )		G	R5F102AAGSP#V0, R5F102A9GSP#V0, R5F102A8GSP#V0, R5F102A7GSP#V0 R5F102AAGSP#X0, R5F102A9GSP#X0, R5F102A8GSP#X0, R5F102A7GSP#X0
		Not mounted	А	R5F103AAASP#V0, R5F103A9ASP#V0, R5F103A8ASP#V0, R5F103A7ASP#V0 R5F103AAASP#X0, R5F103A9ASP#X0, R5F103A8ASP#X0, R5F103A7ASP#X0
			D	R5F103AADSP#V0, R5F103A9DSP#V0, R5F103A8DSP#V0, R5F103A7DSP#V0 R5F103AADSP#X0, R5F103A9DSP#X0, R5F103A8DSP#X0, R5F103A7DSP#X0

Note For fields of application, see Figure 1-1 Part Number, Memory Size, and Package of RL78/G12.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.



#### 1.3 Differences between the R5F102 Products and the R5F103 Products

The following are differences between the R5F102 products and the R5F103 products.

- O Whether the data flash memory is mounted or not
- O High-speed on-chip oscillator oscillation frequency accuracy
- O Number of channels in serial interface
- O Whether the DMA function is mounted or not
- O Whether a part of the safety functions are mounted or not

#### 1.3.1 Data Flash

The data flash memory of 2 KB is mounted on the R5F102 products, but not on the R5F103 products.

Product	Data Flash
R5F102 products	2 KB
R5F1026A, R5F1027A, R5F102AA,	
R5F10269, R5F10279, R5F102A9,	
R5F10268, R5F10278, R5F102A8,	
R5F10267, R5F10277, R5F102A7,	
R5F10266 Note	
R5F103 products	Not mounted
R5F1036A, R5F1037A, R5F103AA,	
R5F10369, R5F10379, R5F103A9,	
R5F10368, R5F10378 R5F103A8,	
R5F10367, R5F10377, R5F103A7,	
R5F10366	

**Note** The RAM in the R5F10266 has capacity as small as 256 bytes. Depending on the customer's program specification, the stack area to execute the data flash library may not be kept and data may not be written to or erased from the data flash memory.

Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.

# 1.3.2 On-chip oscillator characteristics

(1) High-speed on-chip oscillator oscillation frequency of the R5F102 products

Oscillator	Condition	MIN	MAX	Unit
High-speed on-chip	T <sub>A</sub> = -20 to +85°C	-1.0	+1.0	%
oscillator oscillation	T <sub>A</sub> = -40 to -20°C	-1.5	+1.5	
frequency accuracy	T <sub>A</sub> = +85 to +105°C	-2.0	+2.0	

(2) High-speed on-chip oscillator oscillation frequency of the R5F103 products

Oscillator	Condition	MIN	MAX	Unit
High-speed on-chip	T <sub>A</sub> = -40 to + 85°C	-5.0	+5.0	%
oscillator oscillation				
frequency accuracy				

# 1.3.3 Peripheral Functions

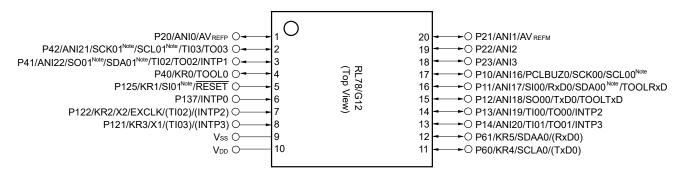
The following are differences in peripheral functions between the R5F102 products and the R5F103 products.

RL78/G12		R5F102 product		R5F103 product		
		20, 24 pin	30 pin product	20, 24 pin	30 pin	
		product		product	product	
Serial interface	UART	1 channel	3 channels	1 channel		
	CSI	2 channels	3 channels	1 channel		
	Simplified I <sup>2</sup> C	2 channels	3 channels	None		
DMA function		2 channels		None		
Safety function	CRC operation	Yes		None		
	RAM guard	Yes		None		
	SFR guard	Yes		None		

# 1.4 Pin Configuration (Top View)

# 1.4.1 20-pin products

<R> • 20-pin plastic LSSOP (4.4 × 6.5 mm, 0.65 mm pitch)



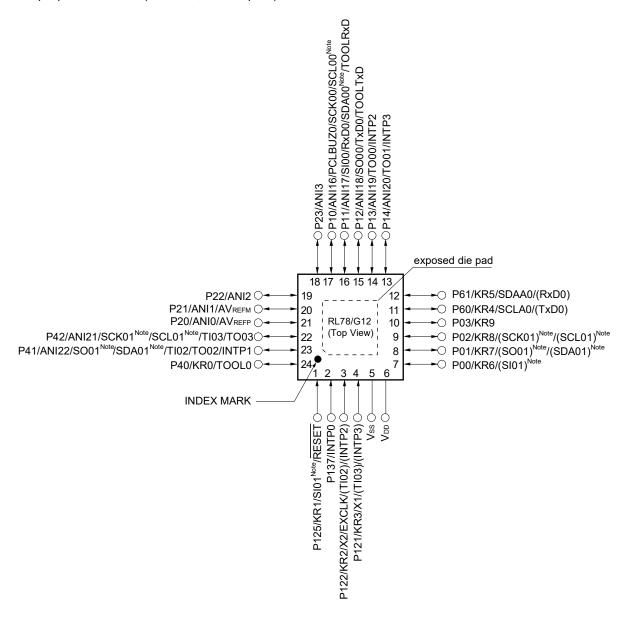
Note Provided only in the R5F102 products.

Remarks 1. For pin identification, see 1.5 Pin Identification.

 Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual.

#### 1.4.2 24-pin products

• 24-pin plastic HWQFN (4 × 4 mm, 0.5 mm pitch)



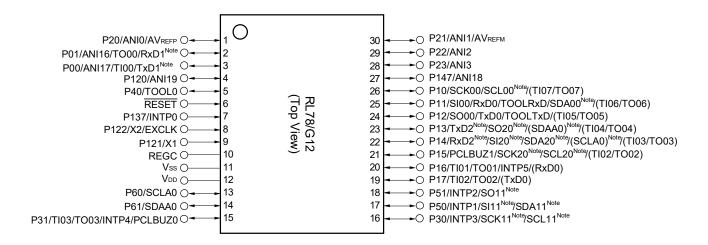
Note Provided only in the R5F102 products.

Remarks 1. For pin identification, see 1.5 Pin Identification.

- Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G12 User's Manual.
- 3. It is recommended to connect an exposed die pad to Vss.

#### 1.4.3 30-pin products

• 30-pin plastic LSSOP (7.62 mm (300), 0.65 mm pitch)



Note Provided only in the R5F102 products.

Caution Connect the REGC pin to Vss via capacitor (0.47 to 1 µF).

Remarks 1. For pin identification, see 1.5 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR)** in the RL78/G12 User's Manual.

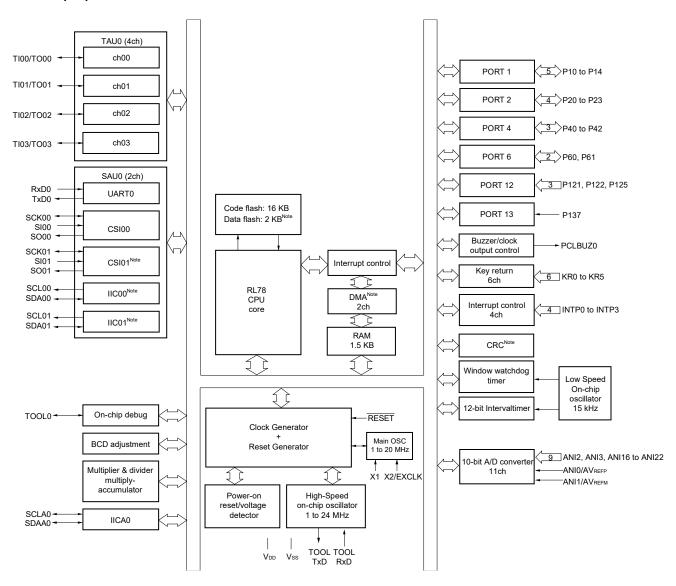
# 1.5 Pin Identification

ANI0 to ANI3,		REGC:	Regulator Capacitance
ANI16 to ANI22:	Analog input	RESET:	Reset
AVREFM:	Analog Reference Voltage Minus	RxD0 to RxD2:	Receive Data
AVREFP:	Analog reference voltage plus	SCK00, SCK01, SCK11,	
EXCLK:	External Clock Input	SCK20:	Serial Clock Input/Output
	(Main System Clock)	SCL00, SCL01,	
INTP0 to INTP5	Interrupt Request From Peripheral	SCL11, SCL20, SCLA0:	Serial Clock Input/Output
KR0 to KR9:	Key Return	SDA00, SDA01, SDA11,	
P00 to P03:	Port 0	SDA20, SDAA0:	Serial Data Input/Output
P10 to P17:	Port 1	SI00, SI01, SI11, SI20:	Serial Data Input
P20 to P23:	Port 2	SO00, SO01, SO11,	
P30 to P31:	Port 3	SO20:	Serial Data Output
P40 to P42:	Port 4	TI00 to TI07:	Timer Input
P50, P51:	Port 5	TO00 to TO07:	Timer Output
P60, P61:	Port 6	TOOL0:	Data Input/Output for Tool
P120 to P122, P125:	Port 12	TOOLRxD, TOOLTxD:	Data Input/Output for External
P137:	Port 13		Device
P147:	Port 14	TxD0 to TxD2:	Transmit Data
PCLBUZ0, PCLBUZ1:	Programmable Clock Output/	VDD:	Power supply
	Buzzer Output	Vss:	Ground
		X1, X2:	Crystal Oscillator (Main System

Clock)

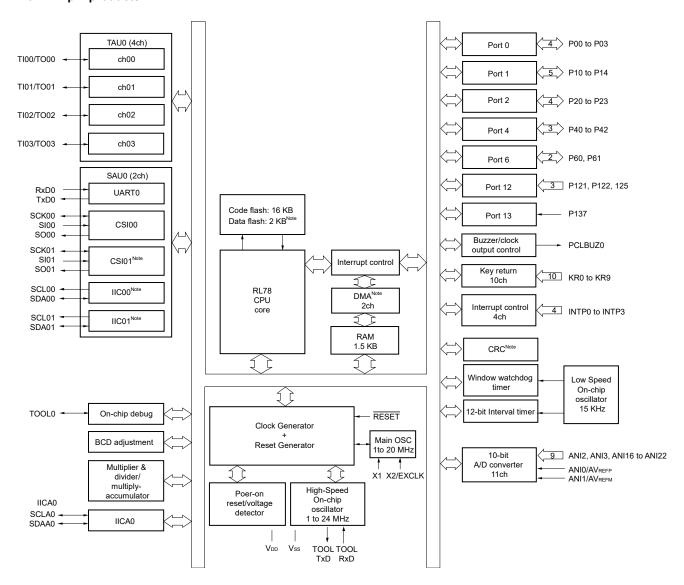
# 1.6 Block Diagram

# 1.6.1 20-pin products



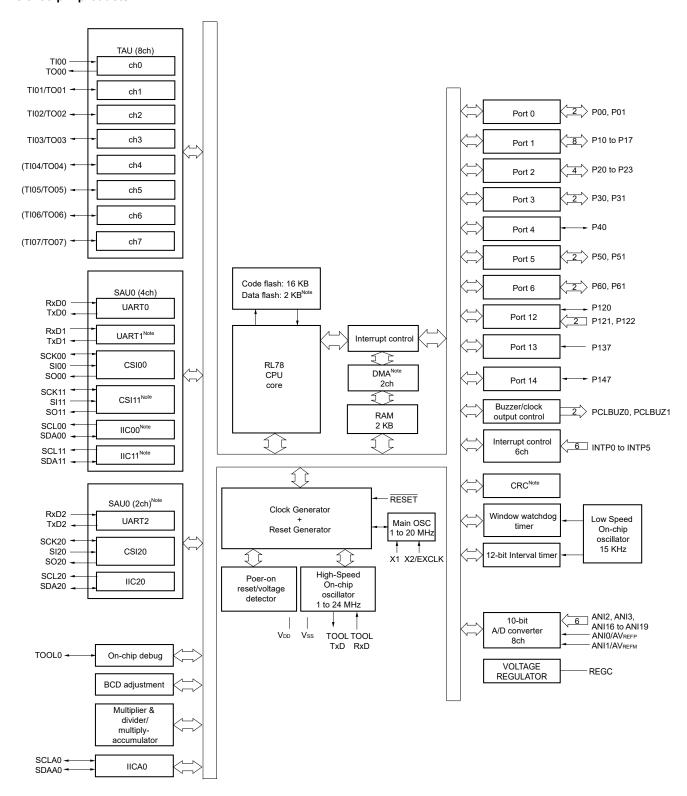
Note Provided only in the R5F102 products.

# 1.6.2 24-pin products



Note Provided only in the R5F102 products.

#### 1.6.3 30-pin products



Note Provided only in the R5F102 products.

**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). See **Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR)** in the RL78/G12 User's Manual.

#### 1.7 Outline of Functions

This outline describes the function at the time when Peripheral I/O redirection register (PIOR) is set to 00H.

(1/2)

	Item	20-	-pin	24-	-pin	30-	-pin	
		R5F1026x	R5F1036x	R5F1027x	R5F1037x	R5F102Ax	R5F103Ax	
Code flas	h memory	2 to 16	KB Note 1		4 to 1	16 KB		
Data flash	n memory	2 KB	_	2 KB	_	2 KB –		
RAM		256 B to	o 1.5 KB	512 B to	1.5 KB	512 B	to 2KB	
Address	space			1 1	МВ			
Main system clock	High-speed system clock	HS (High-spee	X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) HS (High-speed main) mode : 1 to 20 MHz ( $V_{DD}$ = 2.7 to 5.5 V), HS (High-speed main) mode : 1 to 16 MHz ( $V_{DD}$ = 2.4 to 5.5 V), LS (Low-speed main) mode : 1 to 8 MHz ( $V_{DD}$ = 1.8 to 5.5 V)					
	High-speed on-chip oscillator clock	HS (High-spee	HS (High-speed main) mode : 1 to 24 MHz ( $V_{DD}$ = 2.7 to 5.5 V), HS (High-speed main) mode : 1 to 16 MHz ( $V_{DD}$ = 2.4 to 5.5 V), LS (Low-speed main) mode : 1 to 8 MHz ( $V_{DD}$ = 1.8 to 5.5 V)					
Low-spee	ed on-chip oscillator clock	15 kHz (TYP)						
General-p	ourpose register	(8-bit register × 8) × 4 banks						
Minimum	n instruction execution time 0.04167 µs (High-speed on-chip oscillator clock: fiн = 24 MHz operation)							
		0.05 μs (High-	speed system cl	ock: f <sub>MX</sub> = 20 MF	dz operation)			
Instruction	n set	Data transfer (8/16 bits)						
		Adder and subtractor/logical operation (8/16 bits)						
		Multiplication (8 bits × 8 bits)						
	1	Rotate, barrel shift, and bit manipulation (set, reset, test, and Boolean operation), etc.						
I/O port	Total	1	8	2	2	2	26	
	CMOS I/O	(N-ch (	2 D.D. I/O nd voltage]: 4)	(N-ch C	6 D.D. I/O id voltage]: 5)	(N-ch (	:1 D.D. I/O nd voltage]: 9)	
	CMOS input		4	4	4	;	3	
	N-ch open-drain I/O (6 V tolerance)			2	2			
Timer	16-bit timer		4 cha	innels		8 cha	nnels	
	Watchdog timer			1 cha	annel			
	12-bit Interval timer	_		1 cha	annel			
	Timer output		4 cha (PWM outp			8 cha (PWM outpu		

**Notes 1.** The self-programming function cannot be used in the R5F10266 and R5F10366.

- 2. The maximum number of channels when PIOR0 is set to 1.
- 3. The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves). (See 6.9.3 Operation as multiple PWM output function in the RL78/G12 User's Manual.)

Caution When the flash memory is rewritten via a user program, the code flash area and RAM area are used because each library is used. When using the library, refer to RL78 Family Flash Self Programming Library Type01 User's Manual and RL78 Family Data Flash Library Type04 User's Manual.

(2/2)

Item		20-	-pin	24-	-pin	30-pin			
		R5F1026x	R5F1036x	R5F1027x	R5F1037x	R5F102Ax	R5F103Ax		
Clock output/buzzer ou	ıtput			1			2		
		2.44 kHz to 10	MHz: (Peripher	al hardware cloc	ck: fmain = 20 MH	z operation)			
8/10-bit resolution A/D	converter		11 ch	annels		8 cha	innels		
Serial interface		[R5F1026x (20	)-pin), R5F1027	x (24-pin)]					
		CSI: 2 channel	CSI: 2 channels/Simplified I <sup>2</sup> C: 2 channels/UART: 1 channel						
		[R5F102Ax (30	O-pin)]						
		CSI: 1 chann	nel/Simplified I <sup>2</sup> C	C: 1 channel/UAF	RT: 1 channel				
		CSI: 1 chann	nel/Simplified I <sup>2</sup> C	C: 1 channel/UAF	RT: 1 channel				
		CSI: 1 chann	nel/Simplified I <sup>2</sup> C	C: 1 channel/UAF	RT: 1 channel				
		[R5F1036x (20	)-pin), R5F1037	x (24-pin)]					
		CSI: 1 chann	nel/Simplified I <sup>2</sup> C	C: 0 channel/UAF	RT: 1 channel				
		[R5F103Ax (30	[R5F103Ax (30-pin)]						
		CSI: 1 chann	CSI: 1 channel/Simplified I <sup>2</sup> C: 0 channel/UART: 1 channel						
	I <sup>2</sup> C bus			1 cha	annel				
Multiplier and divider/m	nultiply-	• 16 bits × 16 bits = 32 bits (unsigned or signed)							
accumulator		• 32 bits × 32 bits = 32 bits (unsigned)							
		• 16 bits × 16 bits + 32 bits = 32 bits (unsigned or signed)							
DMA controller	1	2 channels	-	2 channels	_	2 channels	_		
Vectored interrupt	Internal	18	16	18	16	26	19		
sources	External		,	5		(	6		
Key interrupt		(	3	1	0	-	_		
Reset		Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution Note Internal reset by RAM parity error Internal reset by illegal-memory access							
Power-on-reset circuit			Power-on-reset: 1.51 V (TYP) Power-down-reset: 1.50 V (TYP)						
Voltage detector		Rising edge	: 1.88 to 4.06 V	(12 stages)					
		Falling edge	: 1.84 to 3.98 V	(12 stages)					
On-chip debug function	า	Provided							
Power supply voltage		V <sub>DD</sub> = 1.8 to 5.	5 V						
Operating ambient tem	perature	$T_A = -40 \text{ to } +8$ (G: Industrial a	,	er applications,	D։ Industrial apբ	olications), T <sub>A</sub> = -	-40 to +105°C		

Note The illegal instruction is generated when instruction code FFH is executed.

Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

# 2. ELECTRICAL SPECIFICATIONS ( $T_A = -40 \text{ to } +85^{\circ}\text{C}$ )

This chapter describes the following electrical specifications.

Target products A: Consumer applications  $T_A = -40$  to +85°C

R5F102xxAxx, R5F103xxAxx

D: Industrial applications T<sub>A</sub> = -40 to +85°C

R5F102xxDxx, R5F103xxDxx

G: Industrial applications when  $T_A$  = -40 to +105°C products is used in the range of  $T_A$  = -40 to +85°C R5F102xxGxx

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product in the RL78/G12 User's Manual.

# 2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (TA = 25°C)

Parameter	Symbols		Conditions	Ratings	Unit
Supply Voltage	V <sub>DD</sub>			-0.5 to + 6.5	V
REGC terminal input	Virego	REGC		-0.3 to +2	V
voltage <sup>Note1</sup>				and -0.3 to V <sub>DD</sub> + 0.3 Note 2	
Input Voltage	VI1	Other than P60, P	61	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	٧
	V <sub>I2</sub>	P60, P61 (N-ch o	oen drain)	-0.3 to 6.5	>
Output Voltage	Vo			-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	>
Analog input voltage	Vai	20-, 24-pin produc	cts: ANI0 to ANI3, ANI16 to ANI22	-0.3 to V <sub>DD</sub> + 0.3	<b>V</b>
		30-pin products: A	NIO to ANI3, ANI16 to ANI19	and -0.3 to AV <sub>REF</sub> (+)+0.3 <sup>Notes 3, 4</sup>	
Output current, high	<b>І</b> он1	Per pin	Other than P20 to P23	-40	mA
		Total of all pins	All the terminals other than P20 to P23	-170	mA
			20-, 24-pin products: P40 to P42	-70	mA
			30-pin products: P00, P01, P40, P120		
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14	-100	mA
			P50, P51, P147		
	<b>І</b> он2	Per pin	P20 to P23	-0.5	mA
		Total of all pins		-2	mA
Output current, low	lo <sub>L1</sub>	Per pin	Other than P20 to P23	40	mA
		Total of all pins	All the terminals other than P20 to P23	ANI3, ANI16 to ANI19  and -0.3 to AV <sub>REF</sub> (+)+0.3 Notes 3, 4  er than P20 to P23  -40  ne terminals other than P20 to P23  24-pin products: P40 to P42  24-pin products: P00, P01, P40, P120  24-pin products: P00 to P03Note 5, to P14  bin products: P10 to P17, P30, P31, P51, P147  to P23  -0.5  -2  er than P20 to P23  40  ne terminals other than P20 to P23  24-pin products: P40 to P42  bin products: P40 to P42  one terminals other than P20 to P23  24-pin products: P40 to P42  bin products: P00, P01, P40, P120  24-pin products: P00 to P03Note 5, to P14, P60, P61	mA
			20-, 24-pin products: P40 to P42 30-pin products: P00, P01, P40, P120	70	mA
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14, P60, P61 30-pin products: P10 to P17, P30, P31, P50, P51, P60, P61, P147	100	mA
	lo <sub>L2</sub>	Per pin	P20 to P23	1	mA
		Total of all pins		5	mA
Operating ambient temperature	TA			-40 to +85	°C
Storage temperature	T <sub>stg</sub>			-65 to +150	°C

- Notes 1. 30-pin product only.
  - 2. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value determines the absolute maximum rating of the REGC pin. Do not use it with voltage applied.
  - 3. Must be 6.5 V or lower.
  - **4.** Do not exceed AVREF(+) + 0.3 V in case of A/D conversion target pin.
  - 5. 24-pin products only.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - **2.** AVREF(+): + side reference voltage of the A/D converter.
  - 3. Vss: Reference voltage



#### 2.2 Oscillator Characteristics

#### 2.2.1 X1 oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	***************************************	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	1.0		20.0	MHz
frequency (fx) <sup>Note</sup>		1.8 V ≤ V <sub>DD</sub> < 2.7 V	1.0		8.0	

**Note** Indicates only permissible oscillator frequency ranges. Refer to AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 oscillator, refer to 5.4 System Clock Oscillator in the RL78/G12 User's Manual.

#### 2.2.2 On-chip oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Oscillators	Parameters	Conditions		MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	fін			1		24	MHz
High-speed on-chip oscillator		R5F102 products	$T_A = -20 \text{ to } +85^{\circ}\text{C}$	-1.0		+1.0	%
clock frequency accuracy			$T_A = -40 \text{ to } -20^{\circ}\text{C}$	-1.5		+1.5	%
		R5F103 products		<b>-</b> 5.0		+5.0	%
Low-speed on-chip oscillator clock frequency	fıL				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

**Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

2. This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.

#### 2.3 DC Characteristics

#### 2.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

(1/4)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Output current, highNote 1	Іон1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42				-10.0 Note 2	mA
		30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			-30.0	mA
		Total of P40 to P42	2.7 V ≤ V <sub>DD</sub> < 4.0 V			-6.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty ≤ 70% Note 3)	1.8 V ≤ V <sub>DD</sub> < 2.7 V			-4.5	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			-80.0	mA
		Total of P00 to P03 <sup>Note 4</sup> , P10 to P14	2.7 V ≤ V <sub>DD</sub> < 4.0 V			-18.0	mA
		30-pin products: Total of P10 to P17, P30, P31, P50, P51, P147 (When duty ≤ 70% Note 3)	1.8 V ≤ V <sub>DD</sub> < 2.7 V			-10.0	mA
		Total of all pins (When duty ≤ 70% <sup>Note 3</sup> )				-100	mA
	<b>І</b> он2	Per pin for P20 to P23				-0.1	mA
		Total of all pins				-0.4	mA

- **Notes 1**. value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> pin to an output pin.
  - 2. However, do not exceed the total current value.
  - 3. The output current value under conditions where the duty factor ≤ 70%.
    If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
    - Total output current of pins = (IoH × 0.7)/(n × 0.01)
      - <Example> Where n = 80% and IoH = -10.0 mA

Total output current of pins =  $(-10.0 \times 0.7)/(80 \times 0.01) \approx -8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. 24-pin products only.

Caution P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products do not output high level in N-ch open-drain mode.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(2/4)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, lowNote 1	lo <sub>L1</sub>	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42				20.0 Note 2	mA
		30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
		Per pin for P60, P61				15.0 Note 2	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			60.0	mA
		30 pin producte:	2.7 V ≤ V <sub>DD</sub> < 4.0 V			9.0	mA
			1.8 V ≤ V <sub>DD</sub> < 2.7 V			1.8	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			80.0	mA
		Total of P00 to P03 <sup>Note 4</sup> ,	2.7 V ≤ V <sub>DD</sub> < 4.0 V			27.0	mA
10		P10 to P14, P60, P61  30-pin products:  Total of P10 to P17, P30, P31, P50, P51, P60, P61, P147  (When duty ≤ 70% Note 3)	1.8 V ≤ V <sub>DD</sub> < 2.7 V			5.4	mA
		Total of all pins (When duty ≤ 70% <sup>Note 3</sup> )				140	mA
	lol2	Per pin for P20 to P23				0.4	mA
		Total of all pins				1.6	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the Vss pin.
  - 2. However, do not exceed the total current value.
  - 3. The output current value under conditions where the duty factor ≤ 70%.
    If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
    - Total output current of pins = (IoL × 0.7)/(n × 0.01)
    - <Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins =  $(10.0 \times 0.7)/(80 \times 0.01) \approx 8.7 \text{ mA}$ 

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. 24-pin products only.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(3/4)

Parameter	Symbol	Condition	S	MIN.	TYP.	MAX.	Unit
Input voltage, high	V <sub>IH1</sub>	Normal input buffer		0.8V <sub>DD</sub>		V <sub>DD</sub>	V
		20-, 24-pin products: P00 to P0 P40 to P42	03 <sup>Note 2</sup> , P10 to P14,				
		30-pin products: P00, P01, P1 P40, P50, P51, P120, P147	0 to P17, P30, P31,				
	V <sub>IH2</sub>	TTL input buffer	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.2		V <sub>DD</sub>	V
		20-, 24-pin products: P10, P11	3.3 V ≤ V <sub>DD</sub> < 4.0 V	2.0		V <sub>DD</sub>	٧
		30-pin products: P01, P10, P11, P13 to P17	1.8 V ≤ V <sub>DD</sub> < 3.3 V	1.5		V <sub>DD</sub>	V
	V <sub>IH3</sub>	P20 to P23		0.7V <sub>DD</sub>		V <sub>DD</sub>	٧
	V <sub>IH4</sub>	P60, P61		0.7V <sub>DD</sub>		6.0	٧
	V <sub>IH5</sub>	P121, P122, P125 <sup>Note 1</sup> , P137, EXCLK, RESET		0.8V <sub>DD</sub>		V <sub>DD</sub>	٧
Input voltage, low	VIL1	Normal input buffer		0		0.2V <sub>DD</sub>	٧
		20-, 24-pin products: P00 to P0 P40 to P42					
		30-pin products: P00, P01, P10 P40, P50, P51, P120, P147					
	V <sub>IL2</sub>	TTL input buffer	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		0.8	<b>V</b>
		20-, 24-pin products: P10, P11	3.3 V ≤ V <sub>DD</sub> < 4.0 V	0		0.5	٧
		30-pin products: P01, P10, P11, P13 to P17	1.8 V ≤ V <sub>DD</sub> < 3.3 V	0		0.32	V
	V <sub>IL3</sub>	P20 to P23		0		0.3V <sub>DD</sub>	V
	V <sub>IL4</sub>	P60, P61		0		0.3V <sub>DD</sub>	V
	VIL5	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0		0.2V <sub>DD</sub>	٧
Output voltage, high	V <sub>OH1</sub>	20-, 24-pin products: P00 to P03 <sup>Note 2</sup> , P10 to P14,	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -10.0 \text{ mA}$	V <sub>DD</sub> -1.5			V
		P40 to P42 30-pin products:	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -3.0 \text{ mA}$	V <sub>DD</sub> -0.7			V
		P00, P01, P10 to P17, P30,	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -2.0 \text{ mA}$	V <sub>DD</sub> -0.6			V
		P147	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V, I <sub>OH1</sub> = −1.5 mA	V <sub>DD</sub> -0.5			V
	V <sub>OH2</sub>	P20 to P23					V

Notes 1. 20, 24-pin products only.

2. 24-pin products only.

Caution The maximum value of V<sub>IH</sub> of pins P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products is V<sub>DD</sub> even in N-ch opendrain mode.

High level is not output in the N-ch open-drain mode.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(4/4)

Parameter	Symbol		Conditio	ns	MIN.	TYP.	MAX.	Unit
Output voltage, low	V <sub>OL1</sub>	20-, 24-pin product P00 to P03 <sup>Note</sup> , P1		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 20.0 \text{ mA}$			1.3	V
		P40 to P42 30-pin products: P0		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 8.5 \text{ mA}$			0.7	V
		D50 D51 D120 D1/17		$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 3.0 \text{ mA}$			0.6	V
				2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V, I <sub>OL1</sub> = 1.5 mA			0.4	V
				1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V, I <sub>OL1</sub> = 0.6 mA			0.4	V
	V <sub>OL2</sub>	P20 to P23		I <sub>OL2</sub> = 400 μA			0.4	V
	Vol3	P60, P61		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 15.0 \text{ mA}$			2.0	V
				$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 5.0 \text{ mA}$			0.4	V
			$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 3.0 \text{ mA}$			0.4	٧	
				$1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 2.0 \text{ mA}$			0.4	V
Input leakage current, high	Ішн1	Other than P121, P122	$V_{I} = V_{DD}$				1	μΑ
	Ішн2	P121, P122 (X1, X2/EXCLK)	$V_{I} = V_{DD}$	Input port or external clock input			1	μA
				When resonator connected			10	μΑ
Input leakage current, low	ILIL1	Other than P121, P122	VI = VSS				-1	μA
	ILIL2	P121, P122 (X1, X2/EXCLK)	Vı = Vss	Input port or external clock input			-1	μΑ
				When resonator connected			-10	μΑ
On-chip pull-up resistance	Ru	20-, 24-pin product P00 to P03 <sup>Note</sup> , P1 P40 to P42, P125, 30-pin products: P0 P10 to P17, P30, F	0 to P14, RESET 00, P01,	V <sub>I</sub> = V <sub>SS</sub> , input port	10	20	100	kΩ
		P50, P51, P120, P						

Note 24-pin products only.

# 2.3.2 Supply current characteristics

#### (1) 20-, 24-pin products

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

(1/2)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD1</sub>	Operating	HS(High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current <sup>Note 1</sup>		mode	main) mode <sup>Note 4</sup>		operation	V <sub>DD</sub> = 3.0 V		1.5		
					Normal	V <sub>DD</sub> = 5.0 V		3.3	5.0	mA
					operation	V <sub>DD</sub> = 3.0 V		3.3	5.0	
				f <sub>IH</sub> = 16 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 5.0 V		2.5	3.7	mA
						V <sub>DD</sub> = 3.0 V		2.5	3.7	
			LS(Low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 3.0 V		1.2	1.8	mA
			main) mode <sup>Note 4</sup>			V <sub>DD</sub> = 2.0 V		1.2	1.8	
	$\begin{array}{c} \text{HS(High-speed} \\ \text{main) mode}^{\text{Note4}} \end{array}  \begin{array}{c} f_{\text{MX}} = 20 \text{ MHz}^{\text{Not}} \\ \text{V}_{\text{DD}} = 5.0 \text{ V} \end{array}$	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		2.8	4.4	mA		
		$V_{DD} = 5.0 \text{ V}$		Resonator connection		3.0	4.6			
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		2.8	4.4	mA
				$V_{DD} = 3.0 \text{ V}$		Resonator connection		3.0	4.6	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.8	2.6	mA
				$V_{DD} = 5.0 \text{ V}$		Resonator connection		1.8	2.6	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.8	2.6	mA
				$V_{DD} = 3.0 \text{ V}$		Resonator connection		1.8	2.6	
			LS(Low-speed	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.1	1.7	mA
			main) mode <sup>Note 4</sup>	$V_{DD} = 3.0 \text{ V}$		Resonator connection		1.1	1.7	
	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup>	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.1	1.7	mA		
				$V_{DD} = 2.0 \text{ V}$		Resonator connection		1.1	1.7	

- Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. When high-speed on-chip oscillator clock is stopped.
  - 3. When high-speed system clock is stopped
  - **4.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode: VDD = 2.7 V to 5.5 V @1 MHz to 24 MHz

 $V_{DD}$  = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fiн: high-speed on-chip oscillator clock frequency
  - 3. Temperature condition of the TYP. value is  $T_A = 25$ °C.

# (1) 20-, 24-pin products

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

(2/2)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub> Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	1210	μA
current Note 1		mode	main) mode <sup>Note 6</sup>		V <sub>DD</sub> = 3.0 V		440	1210	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	950	μA
					V <sub>DD</sub> = 3.0 V		400	950	
			LS (Low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 3.0 V		270	542	μA
			main) mode <sup>Note 6</sup>		V <sub>DD</sub> = 2.0 V		270	542	
			HS (High-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 5.0 V	Resonator connection		450	1170	
			f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA	
			V <sub>DD</sub> = 3.0 V	Resonator connection		450	1170		
			f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	590	μA	
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	660	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$ $V_{DD} = 3.0 \text{ V}$ $f_{MX} = 8 \text{ MHz}^{\text{Note 3}},$	Square wave input		190	590	μA
					Resonator connection		260	660	
			LS (Low-speed		Square wave input		110	360	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 3.0 V	Resonator connection		150	416	
				f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		110	360	μΑ
				V <sub>DD</sub> = 2.0 V	Resonator connection		150	416	
	I <sub>DD3</sub> Note 5	STOP	T <sub>A</sub> = -40°C				0.19	0.50	μΑ
	mode	T <sub>A</sub> = +25°C				0.24	0.50		
		T <sub>A</sub> = +50°C	T <sub>A</sub> = +50°C			0.32	0.80		
	т.	T <sub>A</sub> = +70°C			T <sub>A</sub> = +70°C		0.48	1.20	
		T <sub>A</sub> = +85°C				0.74	2.20		

- **Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator clock is stopped.
  - 4. When high-speed system clock is stopped.
  - **5.** Not including the current flowing into the 12-bit interval timer and watchdog timer.
  - **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode:  $V_{DD}$  = 2.7 V to 5.5 V @1 MHz to 24 MHz

V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except temperature condition of the TYP. value is T<sub>A</sub> = 25°C, other than STOP mode

# (2) 30-pin products

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(1/2)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit														
Supply	I <sub>DD1</sub>	Operating	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA														
current <sup>Note 1</sup>		mode	main) mode <sup>Note 4</sup>		operation	V <sub>DD</sub> = 3.0 V		1.5																
					Normal	V <sub>DD</sub> = 5.0 V		3.7	5.5	mA														
					operation	V <sub>DD</sub> = 3.0 V		3.7	5.5															
				f <sub>IH</sub> = 16 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 5.0 V		2.7	4.0	mA														
						V <sub>DD</sub> = 3.0 V		2.7	4.0															
			LS (Low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 3.0 V		1.2	1.8	mA														
			main) mode Note 4			V <sub>DD</sub> = 2.0 V		1.2	1.8															
	, , , ,	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 5.0 \text{ V}$		Square wave input		3.0	4.6	mA																
				Resonator connection		3.2	4.8																	
				Square wave input		3.0	4.6	mA																
				$V_{DD} = 3.0 \text{ V}$		Resonator connection		3.2	4.8															
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.9	2.7	mA														
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.9	2.7															
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.9	2.7	mA														
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.9	2.7															
			LS (Low-speed	$f_{MX} = 8 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.1	1.7	mA														
		V <sub>DD</sub> = 3.0 V		Resonator connection		1.1	1.7																	
		f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	•		· 1	*	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	•	•	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,		Square wave input		1.1	1.7
				$V_{DD} = 2.0 \text{ V}$		Resonator connection		1.1	1.7															

- Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. When high-speed on-chip oscillator clock is stopped.
  - 3. When high-speed system clock is stopped
  - **4.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode:  $V_{DD}$  = 2.7 V to 5.5 V @1 MHz to 24 MHz

V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Temperature condition of the TYP. value is  $T_A = 25$ °C.

# (2) 30-pin products

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

(2/2)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub> Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	1280	μΑ
current <sup>Note 1</sup>		mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		440	1280	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1000	μA
					V <sub>DD</sub> = 3.0 V		400	1000	
			LS (Low-speed	f <sub>IH</sub> = 8 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 3.0 V		260	530	μA
			main) mode <sup>Note 6</sup>		V <sub>DD</sub> = 2.0 V		260	530	
			HS (High-speed	f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 5.0 V	Resonator connection		450	1170	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1000	μΑ
			V <sub>DD</sub> = 3.0 V	Resonator connection		450	1170		
			f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	600	μΑ	
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	670	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$ $V_{DD} = 3.0 \text{ V}$	Square wave input		190	600	μΑ
					Resonator connection		260	670	
			LS (Low-speed	f <sub>MX</sub> = 8 MHz <sup>Note 3</sup> ,	Square wave input		95	330	μA
			main) mode <sup>Note 6</sup>	V <sub>DD</sub> = 3.0 V	Resonator connection		145	380	
				f <sub>MX</sub> = 8 MHz Note 3,	Square wave input		95	330	μA
				V <sub>DD</sub> = 2.0 V	Resonator connection		145	380	
	I <sub>DD3</sub> Note 5	STOP	T <sub>A</sub> = -40°C				0.18	0.50	μA
	mode	T <sub>A</sub> = +25°C				0.23	0.50		
			T <sub>A</sub> = +50°C				0.30	1.10	
		Т	T <sub>A</sub> = +70°C				0.46	1.90	
			T <sub>A</sub> = +85°C				0.75	3.30	

- Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator clock is stopped.
  - 4. When high-speed system clock is stopped.
  - **5.** Not including the current flowing into the 12-bit interval timer and watchdog timer.
  - **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

HS (High speed main) mode:  $V_{DD}$  = 2.7 V to 5.5 V @1 MHz to 24 MHz

V<sub>DD</sub> = 2.4 V to 5.5 V @1 MHz to 16 MHz

- **Remarks 1.** f<sub>MX</sub>: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except STOP mode, temperature condition of the TYP. value is TA = 25°C.

# (3) Peripheral functions (Common to all products)

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed onchip oscillator operating current	FIL Note 1				0.20		μΑ
12-bit interval timer operating current	ÎTMKA Notes 1, 2, 3				0.02		μΑ
Watchdog timer operating current	IWDT Notes 1, 2, 4	fı∟ = 15 kHz			0.22		μΑ
A/D converter	IADC Notes 1, 5	When conversion at	Normal mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 5.0 V		1.30	1.70	mA
operating current		maximum speed	Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V		0.50	0.70	mA
A/D converter reference voltage operating current	ADREF Note 1				75.0		μΑ
Temperature sensor operating current	TMPS Note 1				75.0		μΑ
LVD operating current	I <sub>LVD</sub> Notes 1, 6				0.08		μΑ
Self- programming operating current	FSP Notes 1, 8				2.00	12.20	mA
BGO operating current	I <sub>BGO</sub> Notes 1, 7				2.00	12.20	mA
SNOOZE	I <sub>SNOZ</sub> Note 1	ADC operation	The mode is performed Note 9		0.50	0.60	mA
operating current			The A/D conversion operations are performed, Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V		1.20	1.44	mA
		CSI/UART operation			0.70	0.84	mA

# Notes 1. Current flowing to the VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3, and IFIL and ITMKA when the 12-bit interval timer operates.
- 4. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- **5.** Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- **6.** Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 7. Current flowing only during data flash rewrite.
- 8. Current flowing only during self programming.
- 9. For shift time to the SNOOZE mode, see 17.3.3 SNOOZE mode in the RL78/G12 User's Manual.

# Remarks 1. fil: Low-speed on-chip oscillator clock frequency

2. Temperature condition of the TYP. value is T<sub>A</sub> = 25°C

# 2.4 AC Characteristics

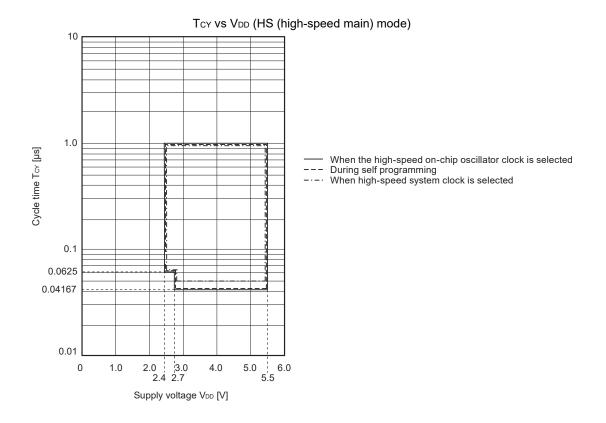
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$ 

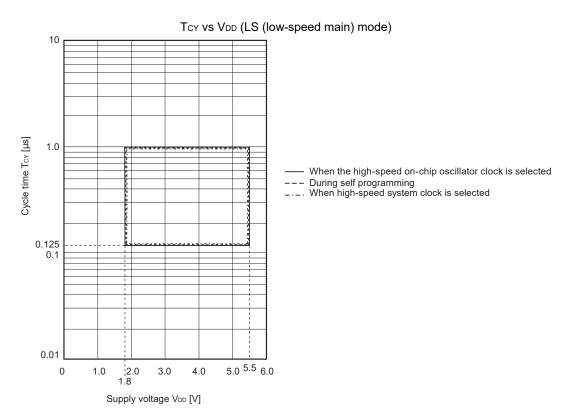
Items	Symbol		Condition	s	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main system	HS (High-	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.04167		1	μs
instruction execution time)		clock (fMAIN) operation	speed main) mode	2.4 V ≤ V <sub>DD</sub> < 2.7 V	0.0625		1	μs
			LS (Low- speed main) mode	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.125		1	μs
		During self	HS (High-	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.04167		1	μs
		programming	speed main) mode	2.4 V ≤ V <sub>DD</sub> < 2.7 V	0.0625		1	μs
			LS (Low- speed main) mode	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.125		1	μs
External main system clock	fex	2.7 V ≤ V <sub>DD</sub> ≤ 5	.5 V		1.0		20.0	MHz
frequency		2.4 V ≤ V <sub>DD</sub> < 2.7 V			1.0		16.0	MHz
		1.8 V ≤ V <sub>DD</sub> < 2.4 V			1.0		8.0	MHz
External main system clock	texh, texL 2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V				24			ns
input high-level width, low-		2.4 V ≤ V <sub>DD</sub> < 2.7 V			30			ns
level width		1.8 V ≤ V <sub>DD</sub> < 2.4 V			60			ns
TI00 to TI07 input high-level width, low-level width	tтін, tті∟				1/fмск + 10			ns
TO00 to TO07 output	fто	4.0 V ≤ V <sub>DD</sub> ≤ 5	i.5 V				12	MHz
frequency		2.7 V ≤ V <sub>DD</sub> < 4	.0 V				8	MHz
		1.8 V ≤ V <sub>DD</sub> < 2	2.7 V				4	MHz
PCLBUZ0, or PCLBUZ1	f <sub>PCL</sub>	4.0 V ≤ V <sub>DD</sub> ≤ 5	i.5 V				16	MHz
output frequency		2.7 V ≤ V <sub>DD</sub> < 4	.0 V				8	MHz
		1.8 V ≤ V <sub>DD</sub> < 2	2.7 V				4	MHz
INTP0 to INTP5 input high- level width, low-level width	tinth, tintl				1			μs
KR0 to KR9 input available width	tkR				250			ns
RESET low-level width	<b>t</b> RSL				10			μs

# Remark fmck: Timer array unit operation clock frequency

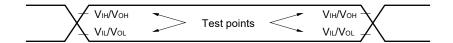
(Operation clock to be set by the timer clock select register 0 (TPS0) and the CKS0n bit of timer mode register 0 (TMR0n). n: Channel number (n = 0 to 7))

# Minimum Instruction Execution Time during Main System Clock Operation

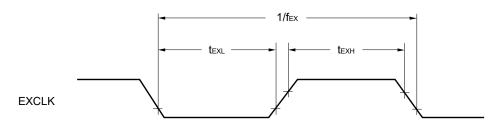




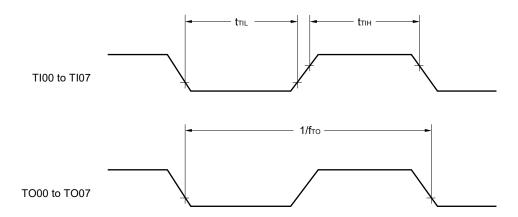
# **AC Timing Test Point**



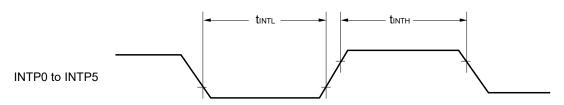
# **External Main System Clock Timing**



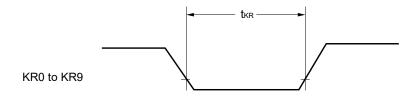
# **TI/TO Timing**



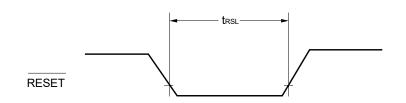
# **Interrupt Request Input Timing**



# **Key Interrupt Input Timing**

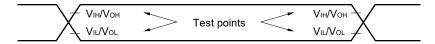


# **RESET** Input Timing



# 2.5 Peripheral Functions Characteristics

# **AC Timing Test Point**



#### 2.5.1 Serial array unit

# (1) During communication at same potential (UART mode)

# $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate				fмск/6		fмск/6	bps
Note 1		Theoretical value of the maximum transfer rate $f_{CLK} = f_{MCK}^{Note 2}$		4.0		1.3	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

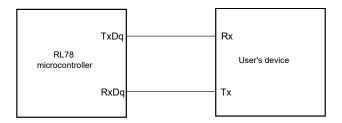
HS (high-speed main) mode: 24 MHz (2.7 V ≤ V<sub>DD</sub> ≤ 5.5 V)

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

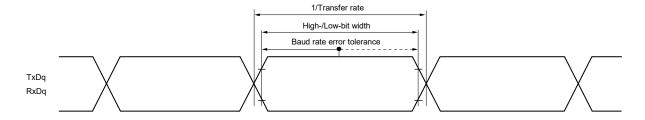
LS (low-speed main) mode: 8 MHz (1.8 V ≤ V<sub>DD</sub> ≤ 5.5 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

# **UART** mode connection diagram (during communication at same potential)



#### **UART** mode bit width (during communication at same potential) (reference)



**Remarks 1.** q: UART number (q = 0 to 2), g: PIM, POM number (g = 0, 1)

2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))

# (2) During communication at same potential (CSI mode) (master mode, SCK00... internal clock output, corresponding CSI00 only)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-speed main)  Mode		LS (low-spe	,	Unit
			MIN.	MAX.	MIN.	MAX.	
SCK00 cycle time	tkcy1	tkcy1 ≥ 2/fclk	83.3		250		ns
SCK00 high-/low-	<b>t</b> кн1,	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	tkcy1/2-7		tkcy1/2-50		ns
level width	t <sub>KL1</sub>	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	tkcy1/2-10		tkcy1/2-50		ns
SI00 setup time	tsik1	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	23		110		ns
(to SCK00↑) Note 1		2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	33		110		ns
SI00 hold time (from SCK00↑) Note 2	t <sub>KSI1</sub>		10		10		ns
Delay time from SCK00↓ to SO00 output Note 3	tkso1	C = 20 pF Note 4		10		10	ns

- **Notes 1.** When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The SI00 setup time becomes "to  $SCK00\downarrow$ " when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - 2. When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The SI00 hold time becomes "from SCK00↓" when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - 3. When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1. The delay time to SO00 output becomes "from SCK00 $\uparrow$ " when DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
  - 4. C is the load capacitance of the SCK00 and SO00 output lines.

Caution Select the normal input buffer for the SI00 pin and the normal output mode for the SO00 and SCK00 pins by using port input mode register 1 (PIM1) and port output mode register 1 (POM1).

- Remarks 1. This specification is valid only when CSI00's peripheral I/O redirect function is not used.
  - fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register 0 (SPS0) and the CKS00 bit of serial mode register 00 (SMR00).)

# (3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	167		500		ns
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	250		500		ns
			1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V	_		500		ns
SCKp high-/low-level width	<b>t</b> кн1,	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V		tксү1/2-12		tkcy1/2-50		ns
	<b>t</b> KL1	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$ $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}$		tксү1/2-18		tkcy1/2-50		ns
				tkcy1/2-38		tkcy1/2-50		ns
		1.8 V ≤ V <sub>DD</sub> ≤	5.5 V	_		tксү1/2-50		ns
SIp setup time (to SCKp↑)  Note 1	tsıĸı	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V		44		110		ns
		2.7 V ≤ V <sub>DD</sub> ≤	5.5 V	44		110		ns
		2.4 V ≤ V <sub>DD</sub> ≤	5.5 V	75		110		ns
		1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V		_		110		ns
SIp hold time (from SCKp↑) Note 2	tksii			19		19		ns
Delay time from SCKp↓ to SOp output Note 3	tkso1	C = 30 pF Note 4			25		25	ns

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp and SCKp pins by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

- Remarks 1. p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products)
  - 2. fmck: Serial array unit operation clock frequency
    (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.))

# (4) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input)

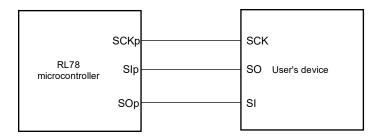
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 5 txc	tkcy2	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	20 MHz < fмск	8/fмск		-		ns
			fмcк ≤ 20 MHz	6/fмск		6/fмск		ns
		2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	16 MHz < fмск	8/fмск		-		ns
			fмcк ≤ 16 MHz	6/fмск		6/fмск		ns
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		6/fмск		6/ƒмск		ns
				and 500		and 500		
		1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V		_		6/fмск		ns
						and 750		
SCKp high-/low-level width	t <sub>KH2</sub> ,	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V		tkcy2/2-7		tkcy2/2-7		ns
	tĸL2	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		tkcy2/2-8		tkcy2/2-8		ns
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		tkcy2/2-18		tkcy2/2-18		ns
		1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V		_		tkcy2/2-18		ns
SIp setup time (to SCKp↑) Note 1	tsik2	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		1/fмск + 20		1/fмск + 30		ns
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		1/fмск + 30		1/fмск + 30		ns
		1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V		_		1/fмск + 30		ns
SIp hold time (from SCKp↑) Note 2	t <sub>KSI2</sub>			1/fмск + 31		1/fмск + 31		ns
Delay time from SCKp↓ to SOp output Note 3	tkso2	C = 30 pF Note 4	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		2/fмск + 44		2/f <sub>MCK</sub> + 110	ns
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		2/fмск + 75		2/fмск + 110	ns
			1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V		-		2/fмск + 110	ns

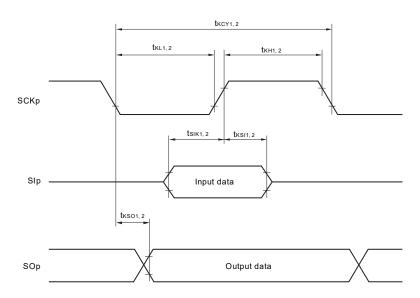
- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps.

Caution Select the normal input buffer for the SIp and SCKp pins and the normal output mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

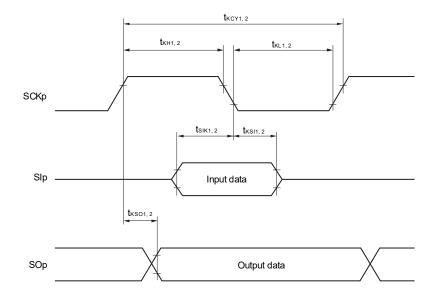
# CSI mode connection diagram (during communication at same potential)



# CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



# CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



(Remarks are listed on the next page.)

- Remarks 1. p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.)
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3: "1, 3" is only for the R5F102 products.))

# (5) During communication at same potential (simplified I<sup>2</sup>C mode)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

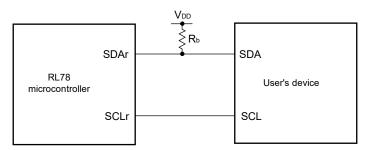
Parameter	Symbol	Conditions	HS (high-speed	HS (high-speed main) Mode		
			LS (low-speed			
			MIN.	MAX.		
SCLr clock frequency	fscL	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V,		400 Note 1	kHz	
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$				
		1.8 V ≤ V <sub>DD</sub> < 2.7 V,		300 Note 1	kHz	
		$C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$				
Hold time when SCLr = "L"	tLOW	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V,	1150		ns	
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$				
		1.8 V ≤ V <sub>DD</sub> < 2.7 V,	1550		ns	
		C <sub>b</sub> = 100 pF, R <sub>b</sub> = 5 kΩ				
Hold time when SCLr = "H"	tніgн	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V,	1150		ns	
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$				
		1.8 V ≤ V <sub>DD</sub> < 2.7 V,	1550		ns	
		$C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$				
Data setup time (reception)	tsu:dat	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V,	1/fмск + 145 Note 2		ns	
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$				
		1.8 V ≤ V <sub>DD</sub> < 2.7 V,	1/fмск + 230 Note 2		ns	
		$C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$				
Data hold time (transmission)	thd:dat	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V,	0	355	ns	
		$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$				
		1.8 V ≤ V <sub>DD</sub> < 2.7 V,	0	405	ns	
		$C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$				

- Notes 1. The value must be equal to or less than fmck/4.
  - 2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

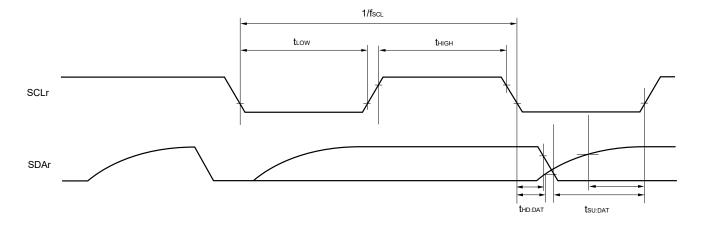
Caution Select the N-ch open drain output (Vop tolerance) mode for SDAr by using port output mode register h (POMh).

(Remarks are listed on the next page.)

#### Simplified I<sup>2</sup>C mode connection diagram (during communication at same potential)



## Simplified I<sup>2</sup>C mode serial transfer timing (during communication at same potential)



- Remarks 1. R<sub>b</sub> [ $\Omega$ ]:Communication line (SDAr) pull-up resistance C<sub>b</sub> [F]: Communication line (SCLr, SDAr) load capacitance
  - 2. r: IIC number (r = 00, 01, 11, 20), h: = POM number (h = 0, 1, 4, 5)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (0, 1, 3))
  - **4.** Simplified I<sup>2</sup>C mode is supported only by the R5F102 products.

#### (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol		Conditions	,	igh-speed n) Mode		w-speed n) Mode	Unit
				MIN.	MAX.	MIN.	MAX.	
Transfer rate Note4		Reception	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V		fмск/6 Note1		fмск/6 Note1	bps
			Theoretical value of the maximum transfer rate f <sub>MCK</sub> = f <sub>CLK</sub> Note3		4.0		1.3	Mbps
			$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$		fмск/6 Note1		fмск/6 Note1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ <b>Note3</b>		4.0		1.3	Mbps
			$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$		fмск/6 Notes1, 2		fмск/6 Notes1, 2	bps
			Theoretical value of the maximum transfer rate  fmck = fclk Note3		4.0		1.3	Mbps
		Transmission	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		Note4		Note4	bps
			Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 1.4$ k $\Omega$ , $V_b = 2.7$ V		2.8 Note5		2.8 Note5	Mbps
			$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$		Note6		Note6	bps
			Theoretical value of the maximum transfer rate $C_b=50 \ pF, \ R_b=2.7 \ k\Omega, \ V_b=2.3 \ V$		1.2 Note7		1.2 Note7	Mbps
			$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$		Notes 2, 8		Notes 2, 8	bps
			Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 5.5$ k $\Omega$ , $V_b = 1.6$ V		0.43 Note9		0.43 <b>Note9</b>	Mbps

### Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

- 2. Use it with  $V_{DD} \ge V_b$ .
- **3.** The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz (2.7 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

LS (low-speed main) mode:  $8 \text{ MHz} (1.8 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V})$ 

**4.** The smaller maximum transfer rate derived by using f<sub>MCK</sub>/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V ≤ V<sub>DD</sub> ≤ 5.5 V and 2.7 V ≤ V<sub>b</sub> ≤ 4.0 V

$$\label{eq:maximum transfer rate} \text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \text{ln } (1-\frac{2.2}{V_b})\} \times 3} \text{ [bps]}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

<sup>\*</sup> This value is the theoretical value of the relative difference between the transmission and reception sides.

- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 4 above to calculate the maximum transfer rate under conditions of the customer.
- The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V ≤ V<sub>DD</sub> < 4.0 V and 2.3 V ≤ V<sub>b</sub> ≤ 2.7 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 7. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 6 above to calculate the maximum transfer rate under conditions of the customer.
- The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V ≤ V<sub>DD</sub> < 3.3 V, 1.6 V ≤ V<sub>b</sub> ≤ 2.0 V

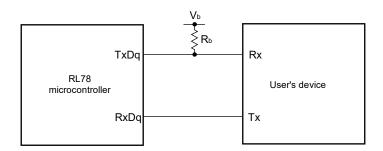
Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{\frac{1}{\text{Transfer rate}} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

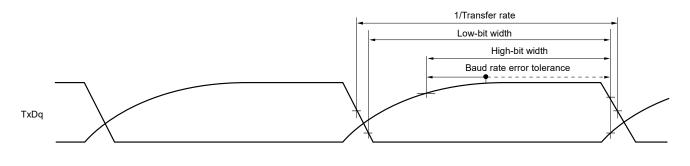
- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 9. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 8 above to calculate the maximum transfer rate under conditions of the customer.

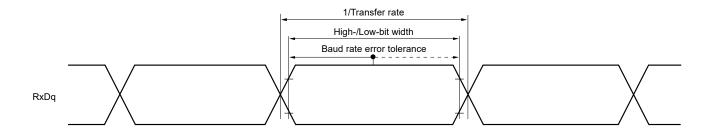
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

#### **UART** mode connection diagram (during communication at different potential)



#### UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.** R<sub>b</sub>[Ω]: Communication line (TxDq) pull-up resistance, C<sub>b</sub>[F]: Communication line (TxDq) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - **2.** q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
  - fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
    - m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))
  - **4.** UART0 of the 20- and 24-pin products supports communication at different potential only when the peripheral I/O redirection function is not used.

## (7) Communication at different potential (2.5 V, 3 V) (CSI mode) (master mode, SCK00... internal clock output, corresponding CSI00 only)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	HS (high main)	h-speed Mode	1	/-speed Mode	Unit
				MIN.	MAX.	MIN.	MAX.	1
SCK00 cycle time	<b>t</b> ксү1	tkcy1≥ 2/fCLK	$ 4.0 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}, $ $ 2.7 \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, $ $ C_{\text{b}} = 20 \text{ pF}, \text{ R}_{\text{b}} = 1.4 \text{ k}\Omega $	200		1150		ns
			$\begin{aligned} 2.7 & \text{ V} \leq \text{V}_{\text{DD}} < 4.0 \text{ V}, \\ 2.3 & \text{V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} & = 20 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{aligned}$	300		1150		ns
SCK00 high-level width	t <sub>KH1</sub>	$4.0 \text{ V} \le \text{V}_{DD} \le 5.$ $C_b = 20 \text{ pF}, R_b =$	5  V, $2.7  V ≤ V$ <sub>b</sub> ≤ $4.0  V$ , = $1.4  kΩ$	tксу1/2 — 50		tксү1/2 — 50		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.$ C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	tксу1/2 — 120		tксү1/2 – 120		ns
SCK00 low-level width	t <sub>KL1</sub>	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V, = 1.4 kΩ	tксу1/2 — 7		tксү1/2 — 50		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.$ $C_b = 20 \text{ pF}, R_b =$	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	tксү1/2 — 10		tксү1/2 — 50		ns
SI00 setup time (to SCK00↑) Note 1	tsıkı	$4.0 \text{ V} \le \text{V}_{DD} \le 5.$ $C_b = 20 \text{ pF}, R_b =$	5  V, $2.7  V ≤ V$ <sub>b</sub> ≤ $4.0  V$ , = $1.4  kΩ$	58		479		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.$ $C_b = 20 \text{ pF}, R_b =$	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	121		479		ns
SI00 hold time (from SCK00↑) Note 1	tksi1	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	5 V, 2.7 V $\leq$ V <sub>b</sub> $\leq$ 4.0 V, = 1.4 kΩ	10		10		ns
		2.7 V ≤ V <sub>DD</sub> < 4. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	10		10		ns
Delay time from SCK00↓ to SO00 output Note 1	tkso1	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V, = 1.4 kΩ		60		60	ns
		2.7 V ≤ V <sub>DD</sub> < 4. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ		130		130	ns
SI00 setup time (to SCK00↓) Note 2	tsıĸı	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	5  V, $2.7  V ≤ V$ <sub>b</sub> ≤ $4.0  V$ , = $1.4  kΩ$	23		110		ns
		2.7 V ≤ V <sub>DD</sub> < 4. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	33		110		ns
SI00 hold time (from SCK00↓) Note 2	tksi1	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V, = 1.4 kΩ	10		10		ns
		2.7 V ≤ V <sub>DD</sub> < 4. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, = 2.7 kΩ	10		10		ns
Delay time from SCK00↑ to SO00 output Note 2	tkso1	4.0 V ≤ V <sub>DD</sub> ≤ 5. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	$5 \text{ V}, 2.7 \text{ V} ≤ \text{V}_b ≤ 4.0 \text{ V},$ = 1.4 kΩ		10		10	ns
		2.7 V ≤ V <sub>DD</sub> < 4. C <sub>b</sub> = 20 pF, R <sub>b</sub> =	0 V, 2.3 V ≤ V <sub>b</sub> ≤ 2.7 V, = 2.7 kΩ		10		10	ns

(Notes, Caution, and Remarks are listed on the next page.)

- Notes 1. When DAP00 = 0 and CKP00 = 0, or DAP00 = 1 and CKP00 = 1
  - 2. When DAP00 = 0 and CKP00 = 1, or DAP00 = 1 and CKP00 = 0.
- Caution Select the TTL input buffer for the SI00 pin and the N-ch open drain output (VDD tolerance) mode for the SO00 pin and SCK00 pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
- Remarks 1. R<sub>b</sub> [Ω]:Communication line (SCK00, SO00) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCK00, SO00) load capacitance, Vb [V]: Communication line voltage
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register 0 (SPS0) and the CKS00 bit of serial mode register 00 (SMR00).)

## (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/3)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	HS (high-spe	•	LS (low-spee	,	Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	300		1150		ns
			$2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$					
		$C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$						
			$2.7 \text{ V} \le \text{V}_{DD} \le 4.0 \text{ V},$	500		1150		ns
			$2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$					
			$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$					
			1.8 V ≤ V <sub>DD</sub> < 3.3 V,	1150		1150		ns
			$1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}^{\text{Note}},$					
			$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$					
SCKp high-level width	t <sub>KH1</sub>	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$		tксү1/2 -75		tkcy1/2-75		ns
		C <sub>b</sub> = 30 pF, R	l <sub>b</sub> = 1.4 kΩ					
		2.7 V ≤ V <sub>DD</sub> <	$4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$	tксү1/2 –170		tkcy1/2-170		ns
		C <sub>b</sub> = 30 pF, R	<sub>b</sub> = 2.7 kΩ					
		1.8 V ≤ V <sub>DD</sub> <	$3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V}^{\text{Note}},$	tkcy1/2 -458		tkcy1/2-458		ns
		C <sub>b</sub> = 30 pF, R	<sub>b</sub> = 5.5 kΩ					
SCKp low-level width	t <sub>KL1</sub>	4.0 V ≤ V <sub>DD</sub> ≤	5.5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V,	tkcy1/2-12		tксү1/2-50		ns
		Сь = 30 pF, R	$t_b = 1.4 \text{ k}\Omega$					
		2.7 V ≤ V <sub>DD</sub> <	4.0 V, 2.3 V ≤ V <sub>b</sub> ≤ 2.7 V,	tксү1/2 –18		tксү1/2-50		ns
		C <sub>b</sub> = 30 pF, R	$k_{\rm b} = 2.7~{\rm k}\Omega$					
	<del> </del>	$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}^{\text{Note}},$		tkcy1/2 -50		tkcy1/2-50		ns
		C₀ = 30 pF, R	<sub>b</sub> = 5.5 kΩ					

Note Use it with  $V_{DD} \ge V_b$ .

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20)

## (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (2/3)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	, ,	h-speed Mode	`	/-speed Mode	Unit
			MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) Note 1	tsıĸı	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	81		479		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	177		479		ns
			479		479		ns
Slp hold time (from SCKp↑) Note 1	tksi1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	19		19		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	19		19		ns
		$ \begin{aligned} &1.8 \text{ V} \leq \text{V}_{\text{DD}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note 2}}, \\ &C_{\text{b}} = 30 \text{ pF}, \ R_{\text{b}} = 5.5 \text{ k}\Omega \end{aligned} $	19		19		ns
Delay time from SCKp↓ to	tkso1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$		100		100	ns
SOp output Note 1		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$		195		195	ns
				483		483	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

(Cautions and Remarks are listed on the next page.)

<sup>2.</sup> Use it with  $V_{DD} \ge V_b$ .

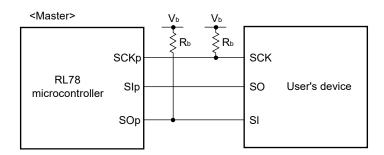
(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

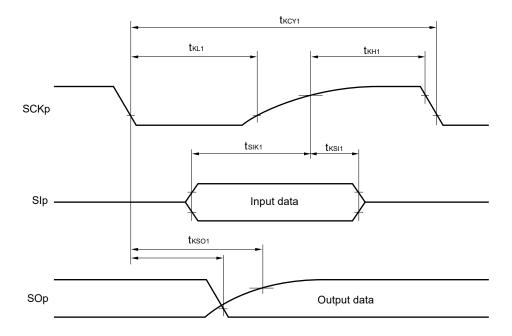
Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode	
			MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↓) Note 1	tsıĸ1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$	44		110		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	44		110		ns
		$1.8 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}^{\text{Note 2}},$ $C_{b} = 30 \text{ pF}, \ R_{b} = 5.5 \text{ k}\Omega$	110		110		ns
SIp hold time (from SCKp↓) Note 1	t <sub>KSI1</sub>	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$	19		19		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	19		19		ns
		$1.8 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}^{\text{Note 2}},$ $C_{b} = 30 \text{ pF}, \ R_{b} = 5.5 \text{ k}\Omega$	19		19		ns
Delay time from SCKp↑ to	tkso1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$		25		25	ns
SOp output Note 1		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$		25		25	ns
		$1.8 \text{ V} \leq \text{V}_{\text{DD}} < 3.3 \text{ V}, 1.6 \text{ V} \leq \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note 2}},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 5.5 \text{ k}\Omega$		25		25	ns

- **Notes 1.** When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. Use it with  $V_{DD} \ge V_b$ .
- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VH and VL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

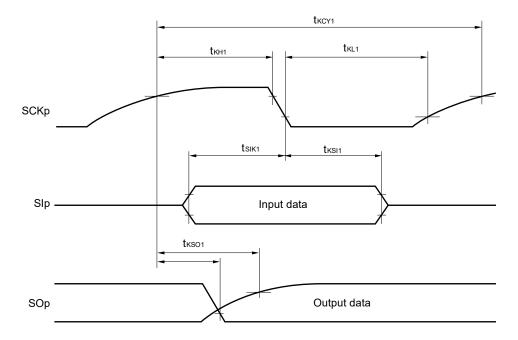
### CSI mode connection diagram (during communication at different potential)



## CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)



## CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



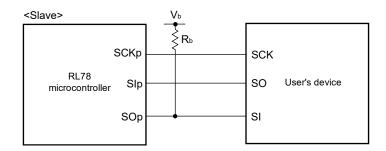
## (9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Co	onditions	HS (high-spe	,	LS (low-spe	•	Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 1	tkcy2	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	12/fмск		-		ns
		$2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$	8 MHz < f <sub>MCK</sub> ≤ 20 MHz	10/fмск		-		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	8/fмск		16/fмск		ns
			fmck ≤ 4 MHz	6/fмск		10/fмск		ns
		2.7 V ≤ V <sub>DD</sub> < 4.0 V,	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	16/fмск		_		ns
		2.3 V ≤ V <sub>b</sub> ≤ 2.7 V	16 MHz < fмck ≤ 20 MHz	14/fмск		1		ns
			8 MHz < f <sub>MCK</sub> ≤ 16 MHz	12/fмск		-		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	8/fмск		16/fмск		ns
			fmck ≤ 4 MHz	6/fмск		10/fмск		ns
		1.8 V ≤ V <sub>DD</sub> < 3.3 V,	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	36/fмск		-		ns
		1.6 V ≤ V <sub>b</sub> ≤ 2.0 V	16 MHz < f <sub>MCK</sub> ≤ 20 MHz	32/fмск		-		ns
		Note 2	8 MHz < f <sub>MCK</sub> ≤ 16 MHz	26/fмск		-		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	16/fмск		16/fмск		ns
			fmck ≤ 4 MHz	10/fмск		10/fмск		ns
SCKp high-/low-level	t <sub>KH2</sub> ,	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	2.7 V ≤ V <sub>b</sub> ≤ 4.0 V	tkcy2/2 - 12		tkcy2/2 - 50		ns
width	t <sub>KL2</sub>	$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$	2.3 V ≤ V <sub>b</sub> ≤ 2.7 V	tkcy2/2 - 18		tkcy2/2 - 50		ns
		1.8 V ≤ V <sub>DD</sub> < 3.3 V,	$1.6~V \leq V_b \leq 2.0~V^{\text{Note 2}}$	tkcy2/2 - 50		tkcy2/2 - 50		ns
SIp setup time	tsik2	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	$2.7 \text{ V} \leq \text{V}_{DD} \leq 4.0 \text{ V}$	1/fmcx + 20		1/f <sub>MCK</sub> + 30		ns
(to SCKp↑) Note 3		$2.7 \text{ V} \le \text{V}_{DD} \le 4.0 \text{ V},$	2.3 V ≤ V <sub>b</sub> ≤ 2.7 V	1/fmck + 20		1/fmck + 30		ns
		1.8 V ≤ V <sub>DD</sub> < 3.3 V,	$1.6 \text{ V} \le \text{V}_{DD} \le 2.0 \text{ V}^{\text{Note 2}}$	1/f <sub>MCK</sub> + 30		1/f <sub>MCK</sub> + 30		ns
SIp hold time (from SCKp↑) Note 4	t <sub>KSI2</sub>			1/fмcк + 31		1/fмск + 31		ns
Delay time from	tkso2	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	2.7 V ≤ V <sub>b</sub> ≤ 4.0 V,		2/fмск +		2/fмск +	ns
SCKp↓ to SOp		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 1.4	kΩ		120		573	
output Note 5		2.7 V ≤ V <sub>DD</sub> < 4.0 V,	2.3 V ≤ V <sub>b</sub> ≤ 2.7 V,		2/fмск +		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 2.7	kΩ		214		573	
		1.8 V ≤ V <sub>DD</sub> < 3.3 V,	$1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V}^{\text{Note 2}},$		2/fмск +		2/fмск +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 5.5	kΩ		573		573	

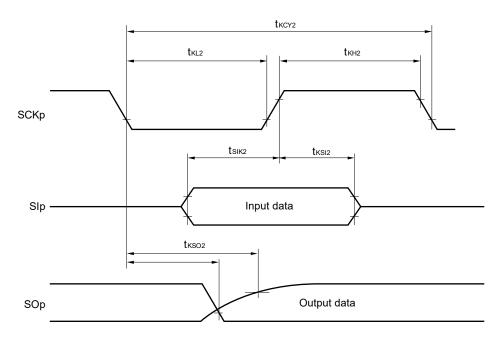
- Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
  - 2. Use it with  $V_{DD} \ge V_b$ .
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Cautions 1. Select the TTL input buffer for the SIp and SCKp pins and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.

#### CSI mode connection diagram (during communication at different potential)

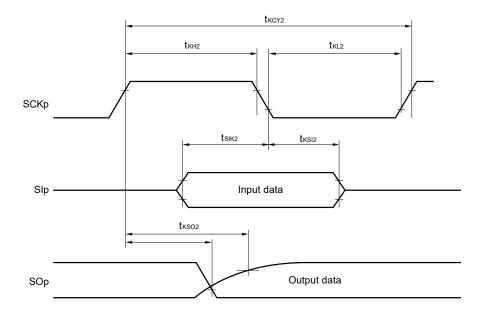


- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - 2. p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 10))

## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



## CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

### (10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I<sup>2</sup>C mode)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

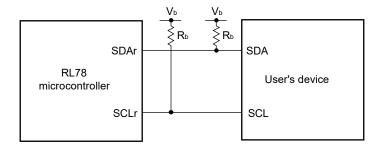
Parameter	Symbol	Conditions		h-speed Mode	-	v-speed Mode	Unit
			MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.8 \text{ k}\Omega$		400 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$		400 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
		$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}, \frac{\text{Note2}}{\text{C}_{b}} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$		300 <sup>Note1</sup>		300 <sup>Note1</sup>	kHz
Hold time when SCLr = "L"	tLOW	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.8 \text{ k}\Omega$	1150		1550		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	1150		1550		ns
		$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}, \frac{\text{Note2}}{\text{C}_{b}} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	1550		1550		ns
Hold time when SCLr = "H"	tнісн	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}\Omega$	675		610		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	600		610		ns
		$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}, \frac{\text{Note2}}{\text{C}_{b}} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	610		610		ns
Data setup time (reception)	tsu:dat	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.8 \text{ k}\Omega$	1/fmck + 190 Note3		1/f <sub>MCK</sub> + 190 Note3		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	1/fmck + 190 Note3		1/f <sub>MCK</sub> + 190 Note3		ns
		$1.8 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}, \\ \text{Note2} \\ \text{C}_{b} = 100 \text{ pF}, \ \text{R}_{b} = 5.5 \text{ k}\Omega$	1/fmck + 190 Note3		1/f <sub>MCK</sub> + 190 Note3		ns
Data hold time (transmission)	thd:dat	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}\Omega$	0	355	0	355	ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	0	355	0	355	ns
		$1.8 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}, \frac{\text{Note2}}{\text{C}_{b}} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	0	405	0	405	ns

Notes 1. The value must be equal to or less than fmck/4.

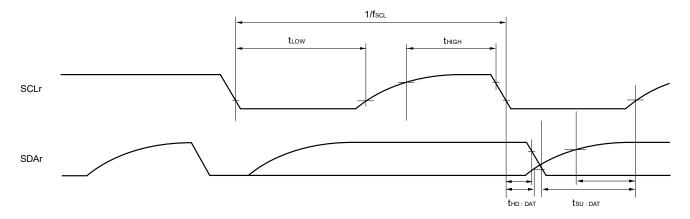
- 2. Use it with  $V_{DD} \ge V_b$ .
- 3. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".
- Cautions 1. Select the TTL input buffer and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SDAr pin and the N-ch open drain output (V<sub>DD</sub> tolerance) mode for the SCLr pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For V<sub>IH</sub> and V<sub>IL</sub>, see the DC characteristics with TTL input buffer selected.
  - 2. IIC01 and IIC11 cannot communicate at different potential.

(Remarks are listed on the next page.)

## Simplified I<sup>2</sup>C mode connection diagram (during communication at different potential)



## Simplified I<sup>2</sup>C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SDAr, SCLr) pull-up resistance, C<sub>b</sub> [F]: Communication line (SDAr, SCLr) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - 2. r: IIC Number (r = 00, 20)
  - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
    - m: Unit number (m = 0,1), n: Channel number (n = 0))
  - **4.** Simplified I<sup>2</sup>C mode is supported only by the R5F102 products.

#### 2.5.2 Serial interface IICA

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions		(high-spee (low-spee	,		Unit
			Standa	rd Mode	Fast	Mode	
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode: fcLk≥ 3.5 MHz			0	400	kHz
		Normal mode: fclk≥ 1 MHz	0	100			kHz
Setup time of restart condition	tsu:sta		4.7		0.6		μs
Hold time <sup>Note 1</sup>	thd:STA		4.0		0.6		μs
Hold time when SCLA0 = "L"	tLOW		4.7		1.3		μs
Hold time when SCLA0 = "H"	thigh		4.0		0.6		μs
Data setup time (reception)	tsu:dat		250		100		ns
Data hold time (transmission)Note 2	thd:dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto		4.0		0.6		μs
Bus-free time	<b>t</b> BUF		4.7		1.3		μs

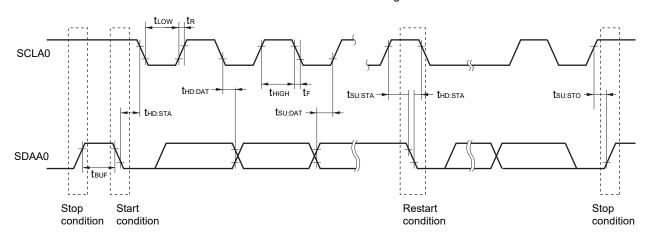
- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
  - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Caution Only in the 30-pin products, the values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.

**Remark** The maximum value of C<sub>b</sub> (communication line capacitance) and the value of R<sub>b</sub> (communication line pull-up resistor) at that time in each mode are as follows.

Normal mode:  $C_b = 400 \text{ pF}, \text{ Rb} = 2.7 \text{ k}\Omega$ Fast mode:  $C_b = 320 \text{ pF}, \text{ Rb} = 1.1 \text{ k}\Omega$ 

## IICA serial transfer timing



## 2.6 Analog Characteristics

#### 2.6.1 A/D converter characteristics

#### Classification of A/D converter characteristics

Input channel		Reference Voltage	
	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = VDD Reference voltage (-) = Vss	Reference voltage (+) = VBGR Reference voltage (-) = AVREFM
ANI0 to ANI3	Refer to <b>2.6.1 (1)</b> .	Refer to 2.6.1 (3).	Refer to <b>2.6.1 (4)</b> .
ANI16 to ANI22	Refer to 2.6.1 (2).		
Internal reference voltage	Refer to 2.6.1 (1).		-
Temperature sensor output voltage			

(1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI2, ANI3, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{AV}_{REFP} \le \text{VDD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	±3.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3			1.2	±7.0 Note 4	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.125		39	μs
		Target pin: ANI2, ANI3	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.1875		39	μs
			1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs
				57		95	μs
		10-bit resolution	3.6 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.375		39	μs
		Target pin: Internal	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.5625		39	μs
	output voltage	temperature sensor output voltage (HS (high-speed main)	2.4 V ≤ VDD ≤ 5.5 V	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution				±0.25	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.50 Note 4	%FSR
Full-scale errorNotes 1, 2	EFS	10-bit resolution				±0.25	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.50 Note 4	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution				±2.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±5.0 Note 4	LSB
Differential linearity error	DLE	10-bit resolution				±1.5	LSB
Note 1		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±2.0 Note 4	LSB
Analog input voltage	VAIN	ANI2, ANI3		0		AVREFP	V
		Internal reference voltage (2.4 V ≤ VDD ≤ 5.5 V, HS	e (high-speed main) mode)	V <sub>BGR</sub> Note 5		٧	
		Temperature sensor outp (2.4 V ≤ VDD ≤ 5.5 V, HS	out voltage (high-speed main) mode)	,	VTMPS25 Note	5	V

(Notes are listed on the next page.)

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - **3.** When  $AV_{REFP} < V_{DD}$ , the MAX. values are as follows.

Overall error: Add ±1.0 LSB to the MAX. value when AVREFP = VDD.

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ±0.5 LSB to the MAX. value when AVREFP = VDD.

- **4.** Values when the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).
- 5. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

## (2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI22

(T<sub>A</sub> = -40 to +85°C, 1.8 V ≤ AV<sub>REFP</sub> ≤ V<sub>DD</sub> ≤ 5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = AV<sub>REFP</sub>, Reference voltage (-) = AV<sub>REFM</sub> = 0 V)

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error Note 1	AINL	10-bit resolution			1.2	±5.0	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3			1.2	±8.5 Note 4	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.125		39	μs
		Target ANI pin: ANI16 to ANI22	2.7 V ≤ VDD ≤ 5.5 V	3.1875		39	μs
			1.8 V ≤ VDD ≤ 5.5 V	17		39	μs
				57		95	μs
Zero-scale error Notes 1, 2	EZS	10-bit resolution				±0.35	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.60 Note 4	%FSR
Full-scale error Notes 1, 2	EFS	10-bit resolution				±0.35	%FSR
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.60 Note 4	%FSR
Integral linearity error Note 1	ILE	10-bit resolution				±3.5	LSB
		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±6.0 Note 4	LSB
Differential linearity	DLE	10-bit resolution				±2.0	LSB
error Note 1		AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±2.5 Note 4	LSB
Analog input voltage	Vain	ANI16 to ANI22		0		AVREFP	V
						and V <sub>DD</sub>	

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - **3.** When  $AV_{REFP} \le V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 4.0$  LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.

Zero-scale error/Full-scale error: Add ±0.20%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AVREFP = VDD.

**4.** When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).

(3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>SS</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

(T<sub>A</sub> = -40 to +85°C, 1.8 V ≤ V<sub>DD</sub> ≤ 5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>DD</sub>, Reference voltage (-) = V<sub>SS</sub>)

Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	±7.0	LSB
					1.2	±10.5 Note 3	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.125		39	μs
		Target pin: ANIO to ANI3,	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.1875		39	μs
		ANI16 to ANI22	1.8 V ≤ VDD ≤ 5.5 V	17		39	μs
				57		95	μs
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.375		39	μs
		Target pin: internal reference	2.7 V ≤ VDD ≤ 5.5 V	3.5625		39	μs
		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	2.4 V ≤ VDD ≤ 5.5 V	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution	1			±0.60	%FSR
						±0.85	%FSR
						Note 3	
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution				±0.60	%FSR
						±0.85 Note 3	%FSR
Integral linearity errorNote 1	ILE	10-bit resolution				±4.0	LSB
						±6.5 Note 3	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
						±2.5 Note 3	LSB
Analog input voltage	Vain	ANI0 to ANI3, ANI16 to ANI2	2	0		V <sub>DD</sub>	V
		Internal reference voltage (2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V, HS (high	n-speed main) mode)	V <sub>BGR</sub> Note 4		V	
		Temperature sensor output v (2.4 V ≤ VDD ≤ 5.5 V, HS (high	o .	`	VTMPS25 Note	4	V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When the conversion time is set to 57  $\mu$ s (min.) and 95  $\mu$ s (max.).
- 4. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM (ADREFM = 1), target pin: ANI0, ANI2, ANI3, and ANI16 to ANI22

(T<sub>A</sub> = -40 to +85°C, 2.4 V ≤ V<sub>DD</sub> ≤ 5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>BGR</sub> Note 3, Reference voltage (-) = AV<sub>REFM</sub> Note 4= 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		bit
Conversion time	tconv	8-bit resolution	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution			±0.60	%FSR
Integral linearity errorNote 1	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	Vain		0		V <sub>BGR</sub> Note 3	V

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - 3. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.
  - 4. When reference voltage (-) = Vss, the MAX. values are as follows.
    Zero-scale error: Add ±0.35%FSR to the MAX. value when reference voltage (-) = AVREFM.
    Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (-) = AVREFM.
    Differential linearity error: Add ±0.2 LSB to the MAX. value when reference voltage (-) = AVREFM.

#### 2.6.2 Temperature sensor/internal reference voltage characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \leq V_{DD} \leq 5.5 \text{ V}, V_{SS} = 0 \text{ V}, HS \text{ (high-speed main) mode}$ 

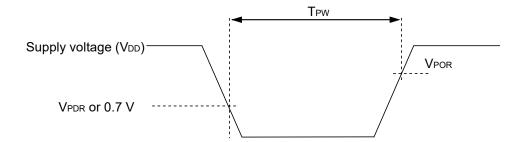
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, T <sub>A</sub> = +25°C		1.05		V
Internal reference voltage	V <sub>BGR</sub>	Setting ADS register = 81H	1.38	1.45	1.50	V
Temperature coefficient	FVTMPS	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

#### 2.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage VPOR		Power supply rise time	1.47	1.51	1.55	V
	V <sub>PDR</sub>	Power supply fall time	1.46	1.50	1.54	V
Minimum pulse width Note	T <sub>PW</sub>		300			μs

Note Minimum time required for a POR reset when  $V_{DD}$  exceeds below  $V_{PDR}$ . This is also the minimum time required for a POR reset from when  $V_{DD}$  exceeds below 0.7 V to when  $V_{DD}$  exceeds  $V_{POR}$  while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



#### 2.6.4 LVD circuit characteristics

## LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection supply voltage	V <sub>L</sub> VD0	Power supply rise time	3.98	4.06	4.14	V
		Power supply fall time	3.90	3.98	4.06	V
	V <sub>LVD1</sub>	Power supply rise time	3.68	3.75	3.82	V
		Power supply fall time	3.60	3.67	3.74	V
	V <sub>LVD2</sub>	Power supply rise time	3.07	3.13	3.19	V
		Power supply fall time	3.00	3.06	3.12	V
	V <sub>L</sub> VD3	Power supply rise time	2.96	3.02	3.08	V
		Power supply fall time	2.90	2.96	3.02	V
	VLVD4	Power supply rise time	2.86	2.92	2.97	V
		Power supply fall time	2.80	2.86	2.91	V
	VLVD5	Power supply rise time	2.76	2.81	2.87	V
		Power supply fall time	2.70	2.75	2.81	V
	VLVD6	Power supply rise time	2.66	2.71	2.76	V
		Power supply fall time	2.60	2.65	2.70	V
	V <sub>LVD7</sub>	Power supply rise time	2.56	2.61	2.66	V
		Power supply fall time	2.50	2.55	2.60	V
	V <sub>L</sub> VD8	Power supply rise time	2.45	2.50	2.55	V
		Power supply fall time	2.40	2.45	2.50	V
	VLVD9	Power supply rise time	2.05	2.09	2.13	V
		Power supply fall time	2.00	2.04	2.08	V
	VLVD10	Power supply rise time	1.94	1.98	2.02	V
		Power supply fall time	1.90	1.94	1.98	V
	V <sub>L</sub> VD11	Power supply rise time	1.84	1.88	1.91	V
		Power supply fall time	1.80	1.84	1.87	V
Minimum pulse width	tıw		300			μs
Detection delay time					300	μs

### LVD detection voltage of interrupt & reset mode

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol		Con	ditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	V <sub>LVDB0</sub>	V <sub>POC2</sub> ,	V <sub>POC1</sub> , V <sub>POC0</sub> = 0, 0, 1, fal	ling reset voltage	1.80	1.84	1.87	٧
mode	V <sub>LVDB1</sub>		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	1.94	1.98	2.02	٧
				Falling interrupt voltage	1.90	1.94	1.98	٧
	V <sub>LVDB2</sub>		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.05	2.09	2.13	٧
				Falling interrupt voltage	2.00	2.04	2.08	٧
	V <sub>LVDB3</sub>		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.07	3.13	3.19	٧
				Falling interrupt voltage	3.00	3.06	3.12	٧
	V <sub>LVDC0</sub>	V <sub>POC2</sub> ,	V <sub>POC1</sub> , V <sub>POC0</sub> = 0, 1, 0, fal	ling reset voltage	2.40	2.45	2.50	V
	V <sub>LVDC1</sub>		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.56	2.61	2.66	٧
				Falling interrupt voltage	2.50	2.55	2.60	٧
	V <sub>LVDC2</sub>		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.66	2.71	2.76	٧
				Falling interrupt voltage	2.60	2.65	2.70	٧
	V <sub>LVDC3</sub>		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.68	3.75	3.82	٧
				Falling interrupt voltage	3.60	3.67	3.74	٧
	V <sub>LVDD0</sub>	V <sub>POC2</sub> ,	V <sub>POC1</sub> , V <sub>POC1</sub> = 0, 1, 1, fal	ling reset voltage	2.70	2.75	2.81	٧
	V <sub>LVDD1</sub>		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.86	2.92	2.97	٧
				Falling interrupt voltage	2.80	2.86	2.91	٧
	V <sub>LVDD2</sub>		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	V <sub>LVDD3</sub>		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.98	4.06	4.14	V
				Falling interrupt voltage	3.90	3.98	4.06	V

## 2.6.5 Power supply voltage rising slope characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

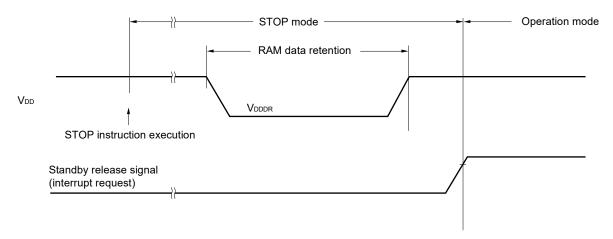
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 2.4 AC Characteristics.

#### 2.7 RAM Data Retention Characteristics

### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{SS} = 0 \text{ V})$

Ì	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
[	Data retention supply voltage	VDDDR		1.46 Note		5.5	V

**Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



#### 2.8 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk		1		24	MHz
Code flash memory rewritable times Notes 1, 2, 3	Cerwr	Retained for 20 years  TA = 85°C	1,000			Times
Data flash memory rewritable times Notes 1, 2, 3		Retained for 1 year  TA = 25°C		1,000,000		
		Retained for 5 years  TA = 85°C	100,000			
		Retained for 20 years  TA = 85°C	10,000			

- **Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.
  - 2. When using flash memory programmer and Renesas Electronics self programming library
  - **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

### 2.9 Dedicated Flash Memory Programmer Communication (UART)

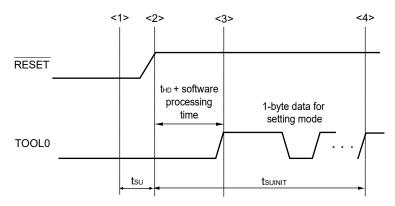
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

## 2.10 Timing of Entry to Flash Memory Programming Modes

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset are released before external reset release			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset are released before external reset release	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset are released before external reset release	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.

tsu: Time to release the external reset after the TOOL0 pin is set to the low level

thd: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

# 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40$ to +105°C)

This chapter describes the following electrical specifications.

Target products G: Industrial applications  $T_A = -40$  to +105°C R5F102xxGxx

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
  - 2. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product in the RL78/G12 User's Manual.
  - 3. Please contact Renesas Electronics sales office for derating of operation under  $T_A = +85^{\circ}C$  to  $+105^{\circ}C$ . Derating is the systematic reduction of load for the sake of improved reliability.

Remark When the RL78 microcontroller is used in the range of T<sub>A</sub> = -40 to +85°C, see **2**. **ELECTRICAL SPECIFICATIONS** (T<sub>A</sub> = -40 to +85°C).

There are following differences between the products "G: Industrial applications ( $T_A = -40$  to +105°C)" and the products "A: Consumer applications, and D: Industrial applications".

Parameter	Applic	ation
	A: Consumer applications, D: Industrial applications	G: Industrial applications
Operating ambient temperature	T <sub>A</sub> = -40 to +85°C	T <sub>A</sub> = -40 to +105°C
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:
Operating voltage range	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 24 MHz	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 24 MHz
	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 16 MHz	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 16 MHz
	LS (low-speed main) mode:	
	1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V@1 MHz to 8 MHz	
High-speed on-chip oscillator	R5F102 products, 1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V:	R5F102 products, 2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V:
clock accuracy	±1.0%@ T <sub>A</sub> = -20 to +85°C	±2.0%@ T <sub>A</sub> = +85 to +105°C
	±1.5%@ T <sub>A</sub> = -40 to -20°C	±1.0%@ T <sub>A</sub> = -20 to +85°C
	R5F103 products, 1.8 V ≤ V <sub>DD</sub> ≤ 5.5 V:	±1.5%@ T <sub>A</sub> = -40 to -20°C
	±5.0%@ T <sub>A</sub> = -40 to +85°C	
Serial array unit	UART	UART
	CSI: fclk/2 (supporting 12 Mbps), fclk/4	CSI: fclk/4
	Simplified I <sup>2</sup> C communication	Simplified I <sup>2</sup> C communication
Voltage detector	Rise detection voltage: 1.88 V to 4.06 V (12 levels)	Rise detection voltage: 2.61 V to 4.06 V
	Fall detection voltage: 1.84 V to 3.98 V (12 levels)	(8 levels)
		Fall detection voltage: 2.55 V to 3.98 V (8 levels)

**Remark** The electrical characteristics of the products G: Industrial applications (TA = -40 to +105°C) are different from those of the products "A: Consumer applications, and D: Industrial applications". For details, refer to **3.1** to **3.10**.



#### 3.1 Absolute Maximum Ratings

Absolute Maximum Ratings ( $T_A = 25$ °C)

Parameter	Symbols		Conditions	Ratings	Unit
Supply Voltage	V <sub>DD</sub>			-0.5 to + 6.5	V
REGC terminal input voltage <sup>Note1</sup>	Virego	REGC		-0.3 to +2.8 and -0.3 to V <sub>DD</sub> + 0.3 Note 2	V
Input Voltage	VI1	Other than P60, F	P61	-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	V
	Vı2	P60, P61 (N-ch o	pen drain)	-0.3 to 6.5	V
Output Voltage	Vo			-0.3 to V <sub>DD</sub> + 0.3 <sup>Note 3</sup>	V
Analog input voltage	Vai	20, 24-pin produc	ts: ANI0 to ANI3, ANI16 to ANI22	-0.3 to V <sub>DD</sub> + 0.3	V
		30-pin products: A	ANI0 to ANI3, ANI16 to ANI19	and -0.3 to AV <sub>REF</sub> (+)+0.3 <sup>Notes 3, 4</sup>	
Output current, high	<b>І</b> он1	Per pin	Other than P20 to P23	-40	mA
		Total of all pins	All the terminals other than P20 to P23	-170	mA
			20-, 24-pin products: P40 to P42 30-pin products: P00, P01, P40, P120	<b>–70</b>	mA
			20-, 24-pin products: P00 to P03 <sup>Note 5</sup> , P10 to P14 30-pin products: P10 to P17, P30, P31, P50, P51, P147	-100	mA
	<b>І</b> он2	Per pin	P20 to P23	-0.5	mA
		Total of all pins		-2	mA
Output current, low	lol1	Per pin	Other than P20 to P23	40	mA
		Total of all pins	All the terminals other than P20 to P23	170	mA
			20-, 24-pin products: P40 to P42 30-pin products: P00, P01, P40, P120	70	mA
			20-, 24-pin products: P00 to P03 Note 5, P10 to P14, P60, P61 30-pin products: P10 to P17, P30, P31, P50, P51, P60, P61, P147	100	mA
	lol2	Per pin	P20 to P23	1	mA
		Total of all pins		5	mA
Operating ambient temperature	Та			-40 to +105	°C
Storage temperature	Tstg			-65 to +150	°C

- Notes 1. 30-pin product only.
  - 2. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value determines the absolute maximum rating of the REGC pin. Do not use it with voltage applied.
  - 3. Must be 6.5 V or lower.
  - 4. Do not exceed AVREF(+) + 0.3 V in case of A/D conversion target pin.
  - **5.** 24-pin products only.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **2.** AVREF(+): + side reference voltage of the A/D converter.
- 3. Vss : Reference voltage



#### 3.2 Oscillator Characteristics

#### 3.2.1 X1 oscillator characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator /	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	1.0		20.0	MHz
frequency (fx) <sup>Note</sup>	crystal oscillator	2.4 V ≤ V <sub>DD</sub> < 2.7 V	1.0		8.0	

**Note** Indicates only permissible oscillator frequency ranges. Refer to AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 oscillator, refer to 5.4 System Clock Oscillator in the RL78/G12 User's Manual.

#### 3.2.2 On-chip oscillator characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Oscillators	Parameters	Cond	litions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	fін			1		24	MHz
High-speed on-chip oscillator		R5F102 products	T <sub>A</sub> = -20 to +85°C	-1.0		+1.0	%
clock frequency accuracy			T <sub>A</sub> = -40 to -20°C	-1.5		+1.5	%
			T <sub>A</sub> = +85 to +105°C	-2.0		+2.0	%
Low-speed on-chip oscillator clock frequency	fiL				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.
  - 2. This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.

#### 3.3 DC Characteristics

#### 3.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(1/4)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high <sup>Note 1</sup>	Іон1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42				-3.0 Note 2	mA
		30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			-9.0	mA
		Total of P40 to P42	2.7 V ≤ V <sub>DD</sub> < 4.0 V			-6.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty ≤ 70% Note 3)	2.4 V ≤ V <sub>DD</sub> < 2.7 V			-4.5	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			-27.0	mA
		Total of P00 to P03 <sup>Note 4</sup> , P10 to P14	2.7 V ≤ V <sub>DD</sub> < 4.0 V			-18.0	mA
		30-pin products: Total of P10 to P17, P30, P31, P50, P51, P147 (When duty ≤ 70% Note 3)	2.4 V ≤ V <sub>DD</sub> < 2.7 V			-10.0	mA
		Total of all pins (When duty ≤ 70% <sup>Note 3</sup> )				-36.0	mA
	<b>І</b> он2	Per pin for P20 to P23				-0.1	mA
		Total of all pins		_		-0.4	mA

- **Notes 1**. value of current at which the device operation is guaranteed even if the current flows from the V<sub>DD</sub> pin to an output pin.
  - 2. However, do not exceed the total current value.
  - 3. The output current value under conditions where the duty factor ≤ 70%.
    If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
    - Total output current of pins = (IoH  $\times$  0.7)/(n  $\times$  0.01)
      - <Example> Where n = 80% and  $I_{OH} = -10.0$  mA

Total output current of pins =  $(-10.0 \times 0.7)/(80 \times 0.01) \approx -8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. 24-pin products only.

Caution P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products do not output high level in N-ch open-drain mode.

(2/4)

Parameter	Symbol	Conditions			TYP.	MAX.	Unit
Output current, low <sup>Note 1</sup>	IOL1	20-, 24-pin products: Per pin for P00 to P03 <sup>Note 4</sup> , P10 to P14, P40 to P42				8.5 Note 2	mA
		30-pin products: Per pin for P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147					
		Per pin for P60, P61				15.0 Note 2	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			25.5	mA
		Total of P40 to P42	2.7 V ≤ V <sub>DD</sub> < 4.0 V			9.0	mA
		30-pin products: Total of P00, P01, P40, P120 (When duty ≤ 70% Note 3)	2.4 V ≤ V <sub>DD</sub> < 2.7 V			1.8	mA
		20-, 24-pin products:	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V			40.0	mA
		Total of P00 to P03 <sup>Note 4</sup> ,	2.7 V ≤ V <sub>DD</sub> < 4.0 V			27.0	mA
		P10 to P14, P60, P61  30-pin products:  Total of P10 to P17, P30, P31, P50, P51, P60, P61, P147  (When duty ≤ 70% Note 3)	2.4 V ≤ V <sub>DD</sub> < 2.7 V			5.4	mA
		Total of all pins (When duty ≤ 70% <sup>Note 3</sup> )				65.5	mA
	lo <sub>L2</sub>	Per pin for P20 to P23				0.4	mA
		Total of all pins		_		1.6	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the Vss pin.
  - 2. However, do not exceed the total current value.
  - 3. The output current value under conditions where the duty factor ≤ 70%.
    If duty factor > 70%: The output current value can be calculated with the following expression (where n represents the duty factor as a percentage).
    - Total output current of pins = (IoL × 0.7)/(n × 0.01)
    - <Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins =  $(10.0 \times 0.7)/(80 \times 0.01) \approx 8.7$  mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. 24-pin products only.

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(3/4)

Parameter	Symbol	Condition	S	MIN.	TYP.	MAX.	Unit
Input voltage, high	V <sub>IH1</sub>	Normal input buffer		0.8V <sub>DD</sub>		V <sub>DD</sub>	V
		20-, 24-pin products: P00 to P0 P40 to P42	)3 <sup>Note 2</sup> , P10 to P14,				
		30-pin products: P00, P01, P1 P40, P50, P51, P120, P147					
	V <sub>IH2</sub>	TTL input buffer	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.2		V <sub>DD</sub>	V
		20-, 24-pin products: P10, P11	3.3 V ≤ V <sub>DD</sub> < 4.0 V	2.0		V <sub>DD</sub>	V
		30-pin products: P01, P10, P11, P13 to P17	2.4 V ≤ V <sub>DD</sub> < 3.3 V	1.5		V <sub>DD</sub>	V
	VIH3	Normal input buffer P20 to P23	·			V <sub>DD</sub>	V
	V <sub>IH4</sub>	P60, P61		0.7V <sub>DD</sub>		6.0	V
	V <sub>IH5</sub>	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0.8V <sub>DD</sub>		V <sub>DD</sub>	V
Input voltage, low	V <sub>IL1</sub>	Normal input buffer		0		0.2V <sub>DD</sub>	V
		20-, 24-pin products: P00 to P0 P40 to P42					
		30-pin products: P00, P01, P10 P40, P50, P51, P120, P147					
	V <sub>IL2</sub>	TTL input buffer	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	0		0.8	V
		20-, 24-pin products: P10, P11	3.3 V ≤ V <sub>DD</sub> < 4.0 V	0		0.5	V
		30-pin products: P01, P10, P11, P13 to P17	2.4 V ≤ V <sub>DD</sub> < 3.3 V	0		0.32	V
	V <sub>IL3</sub>	P20 to P23		0		0.3V <sub>DD</sub>	V
	V <sub>IL4</sub>	P60, P61		0		0.3V <sub>DD</sub>	V
	V <sub>IL5</sub>	P121, P122, P125 <sup>Note 1</sup> , P137,	EXCLK, RESET	0		0.2V <sub>DD</sub>	V
Output voltage, high	Vон1	20-, 24-pin products: P00 to P03 <sup>Note 2</sup> , P10 to P14,	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -3.0 \text{ mA}$	V <sub>DD</sub> -0.7			V
		P40 to P42 30-pin products:	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -2.0 \text{ mA}$	V <sub>DD</sub> -0.6			V
		P00, P01, P10 to P17, P30, P31, P40, P50, P51, P120, P147	$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -1.5 \text{ mA}$	V <sub>DD</sub> -0.5			V
	V <sub>OH2</sub>	P20 to P23	Іон2 = –100 μΑ	V <sub>DD</sub> -0.5			V

Notes 1. 20, 24-pin products only.

2. 24-pin products only.

Caution The maximum value of V<sub>IH</sub> of pins P10 to P12 and P41 for 20-pin products, P01, P10 to P12, and P41 for 24-pin products, and P00, P10 to P15, P17, and P50 for 30-pin products is V<sub>DD</sub> even in N-ch opendrain mode.

High level is not output in the N-ch open-drain mode.

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(4/4)

Parameter	Symbol		Conditio	ins	MIN.	TYP.	MAX.	Unit
Output voltage, low	V <sub>OL1</sub>	20-, 24-pin product P00 to P03 <sup>Note</sup> , P1		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 8.5 \text{ mA}$			0.7	V
		P40 to P42 30-pin products: P0		2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V, I <sub>OL1</sub> = 3.0 mA			0.6	V
		P10 to P17, P30, F P50, P51, P120, P		$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 1.5 \text{ mA}$			0.4	V
				$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 0.6 \text{ mA}$			0.4	٧
	V <sub>OL2</sub>	P20 to P23		I <sub>OL2</sub> = 400 μA			0.4	V
	Vol3	P60, P61		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 15.0 \text{ mA}$			2.0	V
		I <sub>OL1</sub> = 2.7 V I <sub>OL1</sub> = 2.4 V		$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 5.0 \text{ mA}$			0.4	V
				$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 3.0 \text{ mA}$			0.4	V
				$2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 2.0 \text{ mA}$			0.4	V
Input leakage current,	Ішн1	Other than P121, V <sub>I</sub> = V <sub>DD</sub> P122					1	μΑ
	ILIH2	P121, P122 (X1, X2/EXCLK)	V <sub>I</sub> = V <sub>DD</sub>	Input port or external clock input			1	μA
				When resonator connected			10	μΑ
Input leakage current, low	ILIL1	Other than P121, P122	V <sub>I</sub> = V <sub>SS</sub>				-1	μΑ
	ILIL2	P121, P122 (X1, X2/EXCLK)	Vı = Vss	Input port or external clock input			-1	μΑ
				When resonator connected			-10	μA
On-chip pull-up resistance	Ru			V <sub>I</sub> = V <sub>SS</sub> , input port	10	20	100	kΩ
		30-pin products: P0 P10 to P17, P30, F P50, P51, P120, P	P31, P40,					

Note 24-pin products only.

#### 3.3.2 Supply current characteristics

#### (1) 20-, 24-pin products

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(1/2)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD1</sub>	Operating	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current <sup>Note 1</sup>		mode	main) mode Note 4		operation	V <sub>DD</sub> = 3.0 V		1.5		
					Normal	V <sub>DD</sub> = 5.0 V		3.3	5.3	mA
					operation	V <sub>DD</sub> = 3.0 V		3.3	5.3	
				f <sub>IH</sub> = 16 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 5.0 V		2.5	3.9	mA
						V <sub>DD</sub> = 3.0 V		2.5	3.9	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		2.8	4.7	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		3.0	4.8	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		2.8	4.7	mA
				$V_{DD} = 3.0 \text{ V}$		Resonator connection		3.0	4.8	
				f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.8	2.8	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.8	2.8	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$		Square wave input		1.8	2.8	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.8	2.8	

- **Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing data flash rewrite.
  - 2. When high-speed on-chip oscillator clock is stopped.
  - 3. When high-speed system clock is stopped
  - **4.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Temperature condition of the TYP. value is  $T_A = 25$ °C.

#### (1) 20-, 24-pin products

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(2/2)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub> Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	2230	μΑ
current <sup>Note 1</sup>		mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		440	2230	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1650	μA
					V <sub>DD</sub> = 3.0 V		400	1650	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μΑ
				V <sub>DD</sub> = 5.0 V	Resonator connection		450	2000	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μA
				V <sub>DD</sub> = 3.0 V	Resonator connection		450	2000	
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	1010	μA
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	1090	
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	1010	μΑ
				V <sub>DD</sub> = 3.0 V	Resonator connection		260	1090	
	I <sub>DD3</sub> Note 5	STOP	T <sub>A</sub> = -40°C				0.19	0.50	μΑ
		mode	T <sub>A</sub> = +25°C				0.24	0.50	
			$T_A = +50^{\circ}C$ $T_A = +70^{\circ}C$ $T_A = +85^{\circ}C$				0.32	0.80	
							0.48	1.20	
							0.74	2.20	
			T <sub>A</sub> = +105°C				1.50	10.20	

- **Notes 1.** Total current flowing into V<sub>DD</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub> or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator clock is stopped.
  - 4. When high-speed system clock is stopped.
  - 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
  - **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except temperature condition of the TYP. value is  $T_A = 25$ °C, other than STOP mode

#### (2) 30-pin products

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(1/2)

<u> </u>	• ,		D = 0.0 t, too	• • ,						\ .,_
Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD1</sub>	Operating	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 3</sup>	Basic	V <sub>DD</sub> = 5.0 V		1.5		mA
current <sup>Note 1</sup>		mode	main) mode Note 4		operation	V <sub>DD</sub> = 3.0 V		1.5		
					Normal	V <sub>DD</sub> = 5.0 V		3.7	5.8	mA
					operation	V <sub>DD</sub> = 3.0 V		3.7	5.8	
				f <sub>IH</sub> = 16 MHz <sup>Note 3</sup>		V <sub>DD</sub> = 5.0 V		2.7	4.2	mA
						V <sub>DD</sub> = 3.0 V		2.7	4.2	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		3.0	4.9	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		3.2	5.0	
				$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$		Square wave input		3.0	4.9	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		3.2	5.0	
				f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.9	2.9	mA
				V <sub>DD</sub> = 5.0 V		Resonator connection		1.9	2.9	
				f <sub>MX</sub> = 10 MHz <sup>Note 2</sup> ,		Square wave input		1.9	2.9	mA
				V <sub>DD</sub> = 3.0 V		Resonator connection		1.9	2.9	

- Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. When high-speed on-chip oscillator clock is stopped.
  - 3. When high-speed system clock is stopped
  - **4.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - **3.** Temperature condition of the TYP. value is  $T_A = 25$ °C.

#### (2) 30-pin products

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(2/2)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I <sub>DD2</sub> Note 2	HALT	HS (High-speed	f <sub>IH</sub> = 24 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		440	2300	μΑ
current Note 1		mode	main) mode Note 6		V <sub>DD</sub> = 3.0 V		440	2300	
				f <sub>IH</sub> = 16 MHz <sup>Note 4</sup>	V <sub>DD</sub> = 5.0 V		400	1700	μΑ
					V <sub>DD</sub> = 3.0 V		400	1700	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μΑ
				V <sub>DD</sub> = 5.0 V	Resonator connection		450	2000	
				f <sub>MX</sub> = 20 MHz <sup>Note 3</sup> ,	Square wave input		280	1900	μΑ
				V <sub>DD</sub> = 3.0 V	Resonator connection		450	2000	
			f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	1020	μA	
				V <sub>DD</sub> = 5.0 V	Resonator connection		260	1100	
				f <sub>MX</sub> = 10 MHz <sup>Note 3</sup> ,	Square wave input		190	1020	μΑ
				V <sub>DD</sub> = 3.0 V	Resonator connection		260	1100	
	I <sub>DD3</sub> Note 5	STOP	T <sub>A</sub> = -40°C				0.18	0.50	μΑ
		mode	T <sub>A</sub> = +25°C				0.23	0.50	
			T <sub>A</sub> = +50°C				0.30	1.10	
			T <sub>A</sub> = +70°C T <sub>A</sub> = +85°C				0.46	1.90	
							0.75	3.30	
			T <sub>A</sub> = +105°C				2.94	15.30	

- Notes 1. Total current flowing into VDD, including the input leakage current flowing when the level of the input pin is fixed to VDD or Vss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator clock is stopped.
  - 4. When high-speed system clock is stopped.
  - 5. Not including the current flowing into the 12-bit interval timer and watchdog timer.
  - **6.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as follows.

- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: high-speed on-chip oscillator clock frequency
  - 3. Except STOP mode, temperature condition of the TYP. value is  $T_A = 25$ °C.

#### (3) Peripheral functions (Common to all products)

#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed onchip oscillator operating current	FIL Note 1				0.20		μΑ
12-bit interval timer operating current	ITMKA Notes 1, 2, 3				0.02		μΑ
Watchdog timer operating current	WDT Notes 1, 2, 4	fı∟ = 15 kHz	fiL = 15 kHz		0.22		μΑ
A/D converter	IADC	When conversion	Normal mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 5.0 V		1.30	1.70	mA
operating current	Notes 1, 5		Low voltage mode, AV <sub>REFP</sub> = V <sub>DD</sub> = 3.0 V		0.50	0.70	mA
A/D converter reference voltage operating current	ladref Note 1				75.0		μΑ
Temperature sensor operating current	ITMPS Note 1				75.0		μΑ
LVD operating current	ILVD Notes 1, 6				0.08		μΑ
Self-programming operating current	IFSP Notes 1, 8				2.00	12.20	mA
BGO operating current	BGO Notes 1, 7				2.00	12.20	mA
SNOOZE operating	Isnoz	ADC operation	The mode is performed Note 9		0.50	1.10	mA
current	Note 1		The A/D conversion operations are performed, Low voltage mode, AVREFP = VDD = 3.0 V		1.20	2.04	mA
		CSI/UART operation	1		0.70	1.54	mA

#### Notes 1. Current flowing to the VDD.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3, and IFIL and ITMKA when the 12-bit interval timer operates.
- **4.** Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- **5.** Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- **6.** Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 7. Current flowing only during data flash rewrite.
- 8. Current flowing only during self programming.
- 9. For shift time to the SNOOZE mode, see 17.3.3 SNOOZE mode in the RL78/G12 User's Manual.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

2. Temperature condition of the TYP. value is T<sub>A</sub> = 25°C

#### 3.4 AC Characteristics

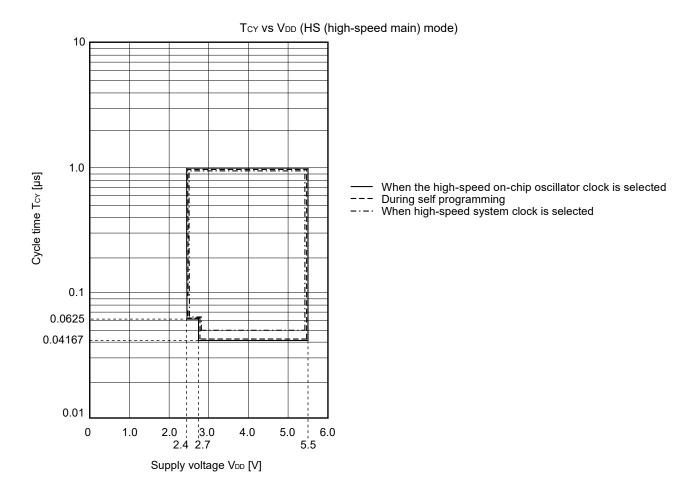
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Items	Symbol		Condition	s	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main system	HS (High-	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.04167		1	μs
instruction execution time)		clock (fMAIN) operation	speed main) mode	2.4 V ≤ V <sub>DD</sub> < 2.7 V	0.0625		1	μs
		During self	HS (High-	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	0.04167		1	μs
		programming	speed main) mode	2.4 V ≤ V <sub>DD</sub> < 2.7 V	0.0625		1	μs
External main system clock	fex	2.7 V ≤ V <sub>DD</sub> ≤ 5.	5 V		1.0		20.0	MHz
frequency		2.4 V ≤ V <sub>DD</sub> < 2	.7 V		1.0		16.0	MHz
External main system clock	texh, texl	2.7 V ≤ V <sub>DD</sub> ≤ 5	1.7 V ≤ V <sub>DD</sub> ≤ 5.5 V					ns
input high-level width, low- level width		2.4 V ≤ V <sub>DD</sub> < 2.	.7 V		30			ns
TI00 to TI07 input high-level width, low-level width	trıн, trı∟				1/fмск + 10			ns
TO00 to TO07 output	fто	4.0 V ≤ V <sub>DD</sub> ≤ 5	.5 V				12	MHz
frequency		2.7 V ≤ V <sub>DD</sub> < 4.	.0 V				8	MHz
		2.4 V ≤ V <sub>DD</sub> < 2	.7 V				4	MHz
PCLBUZ0, or PCLBUZ1	<b>f</b> PCL	4.0 V ≤ V <sub>DD</sub> ≤ 5	.5 V				16	MHz
output frequency		2.7 V ≤ V <sub>DD</sub> < 4	.0 V				8	MHz
		2.4 V ≤ V <sub>DD</sub> < 2	.7 V				4	MHz
INTP0 to INTP5 input high- level width, low-level width	tinth, tintl				1			μs
KR0 to KR9 input available width	tkr				250			ns
RESET low-level width	trsl				10			μs

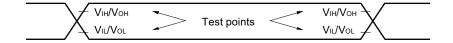
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the timer clock select register 0 (TPS0) and the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

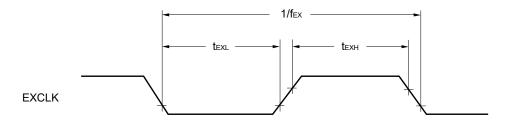
#### Minimum Instruction Execution Time during Main System Clock Operation



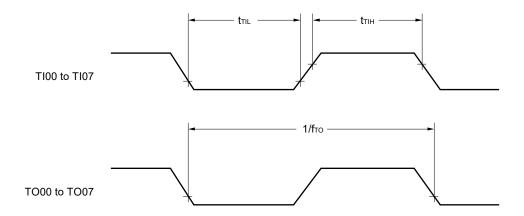
#### **AC Timing Test Point**



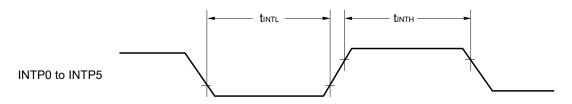
#### **External Main System Clock Timing**



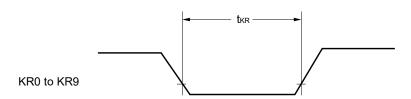
### **TI/TO Timing**



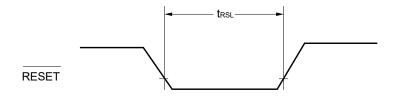
### **Interrupt Request Input Timing**



### **Key Interrupt Input Timing**

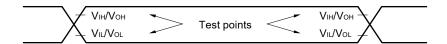


### **RESET Input Timing**



#### 3.5 Peripheral Functions Characteristics

#### **AC Timing Test Point**



#### 3.5.1 Serial array unit

#### (1) During communication at same potential (UART mode)

### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

	, ,	, ,	1		
Parameter	Symbol	Conditions	HS (high-spee	Unit	
			MIN.	MAX.	
Transfer rate				fмск/12	bps
Note 1		Theoretical value of the maximum transfer rate $f_{CLK} = f_{MCK}^{Note \ 2}$		2.0	Mbps

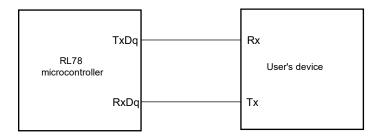
- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.
  - 2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz (2.7 V ≤ V<sub>DD</sub> ≤ 5.5 V)

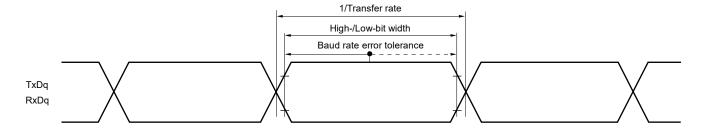
16 MHz  $(2.4 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V})$ 

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

#### **UART** mode connection diagram (during communication at same potential)



#### UART mode bit width (during communication at same potential) (reference)



- **Remarks 1.** q: UART number (q = 0 to 2), g: PIM, POM number (g = 0, 1)
  - 2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))

### (2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions HS (high-speed main) M		d main) Mode	Unit	
				MIN.	MAX.		
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fcLk	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	334		ns	
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	500		ns	
SCKp high-/low-level width	<b>t</b> кн1,	4.0 V ≤ V <sub>DD</sub> ≤ 5	.5 V	tkcy1/2-24		ns	
	t <sub>KL1</sub>	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		tkcy1/2-36		ns	
		2.4 V ≤ V <sub>DD</sub> ≤ 5	.5 V	tkcy1/2-76		ns	
SIp setup time (to SCKp↑) Note 1	tsıĸı	4.0 V ≤ V <sub>DD</sub> ≤ 5	.5 V	66		ns	
		2.7 V ≤ V <sub>DD</sub> ≤ 5	.5 V	66		ns	
		2.4 V ≤ V <sub>DD</sub> ≤ 5	.5 V	113		ns	
SIp hold time (from SCKp↑) Note 2	<b>t</b> KSI1			38		ns	
Delay time from SCKp↓ to SOp output Note 3	tkso1	C = 30 pF Note 4			50	ns	

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp and SCKp pins by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

Remarks 1. p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)

2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3))

### (3) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input)

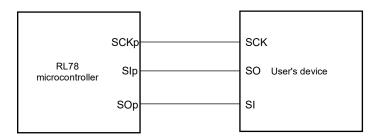
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Con	ditions	HS (high-speed	main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note 5	tkcy2	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V	20 MHz < fмск	16/fмск		ns
			fмcк≤ 20 MHz	12/fмск		ns
		2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	16 MHz < fмск	16/fмск		ns
			fмcк ≤ 16 MHz	12/fмск		ns
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	·	12/fмск		ns
				and 1000		
SCKp high-/low-level width	<b>t</b> кн2,	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V		tксү2/2-14		ns
	t <sub>KL2</sub>	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		tксү2/2-16		ns
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		tkcy2/2-36		ns
SIp setup time (to SCKp↑)	tsık2	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		1/fмcк + 40		ns
Note 1		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		1/fмск + 60		ns
SIp hold time (from SCKp↑) Note 2	tksi2			1/fмск + 62		ns
Delay time from SCKp↓ to SOp output Note 3	tkso2	C = 30 pF Note 4	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V		2/fмcк + 66	ns
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V		2/fмcк + 113	ns

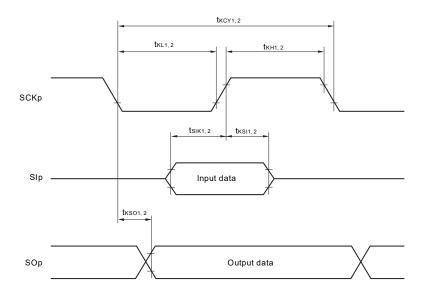
- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
  - 4. C is the load capacitance of the SOp output lines.
  - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps.

Caution Select the normal input buffer for the SIp and SCKp pins and the normal output mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode registers 0, 1, 4 (POM0, POM1, POM4).

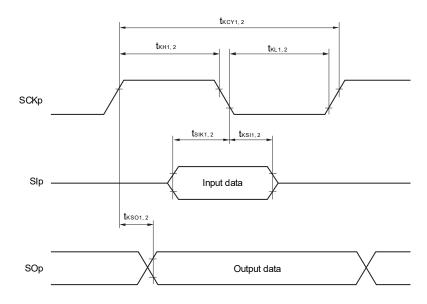
#### CSI mode connection diagram (during communication at same potential)



# CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



### CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remarks 1.** p: CSI number (p = 00, 01, 11, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0, 1, 3)

2. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0,1), n: Channel number (n = 0, 1, 3))

#### (4) During communication at same potential (simplified I<sup>2</sup>C mode)

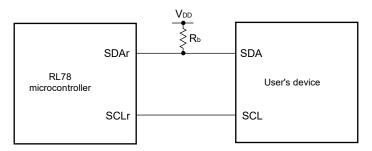
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-speed main) Mode		Unit
			MIN.	MAX.	
SCLr clock frequency	fscL	$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$		100 Note 1	kHz
Hold time when SCLr = "L"	tLOW	$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$	4600		ns
Hold time when SCLr = "H"	thigh	$C_b$ = 100 pF, $R_b$ = 3 k $\Omega$	4600		ns
Data setup time (reception)	tsu:dat	$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$	1/f <sub>MCK</sub> + 580 Note 2		ns
Data hold time (transmission)	thd:dat	$C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$	0	1420	ns

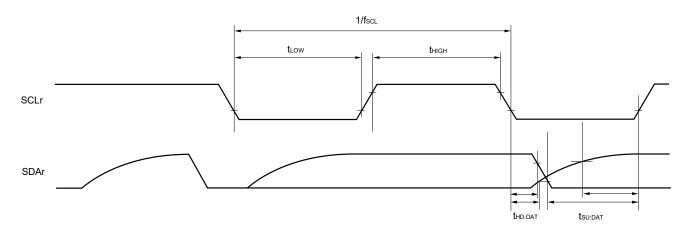
- Notes 1. The value must be equal to or less than fmck/4.
  - 2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".

Caution Select the N-ch open drain output (VDD tolerance) mode for SDAr by using port output mode register h (POMh).

#### Simplified I<sup>2</sup>C mode connection diagram (during communication at same potential)



#### Simplified I<sup>2</sup>C mode serial transfer timing (during communication at same potential)



**Remarks 1.** R<sub>b</sub>  $[\Omega]$ :Communication line (SDAr) pull-up resistance

Cb [F]: Communication line (SCLr, SDAr) load capacitance

- 2. r: IIC number (r = 00, 01, 11, 20), h: = POM number (h = 0, 1, 4, 5)
- 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0, 1), n: Channel number (0, 1, 3))

### (5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	` `	speed main) ode	Unit
				MIN.	MAX.	bps Mbps bps Mbps bps Mbps Mbps
Transfer rate Note4		Reception	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		fмcк/12 Note 1	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 2		2.0	Mbps
			$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$		fмcк/12 Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		2.0	Mbps
			$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$		fмcк/12 Note 1	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		2.0	Mbps
		Transmission	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		Note 3	bps
			Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 1.4$ k $\Omega$ , $V_b = 2.7$ V		2.0 Note 4	Mbps
			$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$		Note 5	bps
			Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 2.7$ k $\Omega$ , $V_b = 2.3$ V		1.2 Note 6	Mbps
			$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$		Notes 2, 7	bps
			Theoretical value of the maximum transfer rate $C_b = 50$ pF, $R_b = 5.5$ k $\Omega$ , $V_b = 1.6$ V		0.43 Note 8	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz (2.7 V ≤ V<sub>DD</sub> ≤ 5.5 V)

16 MHz (2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V)

**3.** The smaller maximum transfer rate derived by using fmck/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V  $\leq$  VDD  $\leq$  5.5 V and 2.7 V  $\leq$  Vb  $\leq$  4.0 V

$$\label{eq:maximum transfer rate} \text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln{(1-\frac{2.2}{V_b})}\} \times 3} \text{ [bps]}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{\frac{1}{(\text{Transfer rate}) \times \text{Number of transferred bits}}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 4. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.
- 5. The smaller maximum transfer rate derived by using fmck/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V ≤ V<sub>DD</sub> < 4.0 V and 2.3 V ≤ V<sub>b</sub> ≤ 2.7 V

$$\label{eq:maximum transfer rate} \text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \text{ln } (1-\frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 6. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 5 above to calculate the maximum transfer rate under conditions of the customer.
- 7. The smaller maximum transfer rate derived by using fmck/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.4 V ≤ V<sub>DD</sub> < 3.3 V, 1.6 V ≤ V<sub>b</sub> ≤ 2.0 V

Maximum transfer rate = 
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

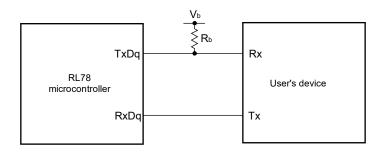
Baud rate error (theoretical value) = 
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- \* This value is the theoretical value of the relative difference between the transmission and reception sides.
- 8. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 7 above to calculate the maximum transfer rate under conditions of the customer.

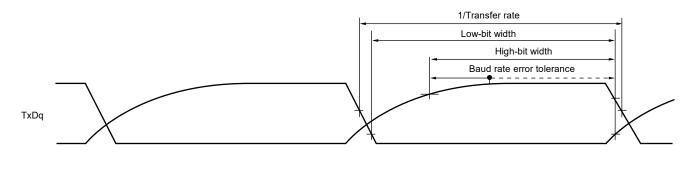
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

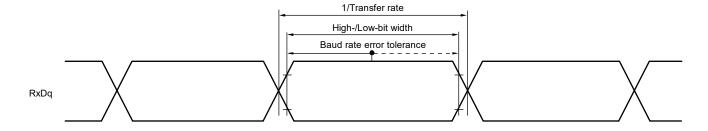


#### UART mode connection diagram (during communication at different potential)



#### UART mode bit width (during communication at different potential) (reference)





- **Remarks 1.** R<sub>b</sub>[Ω]: Communication line (TxDq) pull-up resistance, C<sub>b</sub>[F]: Communication line (TxDq) load capacitance, V<sub>b</sub>[V]: Communication line voltage
  - **2.** q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
  - fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
    - m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))
  - **4.** UART0 of the 20- and 24-pin products supports communication at different potential only when the peripheral I/O redirection function is not used.

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (1/3)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	HS (high-speed	d main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time	tkcy1	tkcy1 ≥ 4/fclk	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$	600		ns
			$2.7 \text{ V} \le V_b \le 4.0 \text{ V},$			
			$C_b$ = 30 pF, $R_b$ = 1.4 k $\Omega$			
			$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V},$	1000		ns
			$2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$			
			$C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$			
			2.4 V ≤ V <sub>DD</sub> < 3.3 V,	2300		ns
			1.6 V ≤ V <sub>b</sub> ≤ 2.0 V,			
			$C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$			
SCKp high-level width	t <sub>KH1</sub>	4.0 V ≤ V <sub>DD</sub> ≤ 5	5.5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V,	tксү1/2 -150		ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub>	= 1.4 kΩ			
		2.7 V ≤ V <sub>DD</sub> < 4	4.0 V, 2.3 V ≤ V <sub>b</sub> ≤ 2.7 V,	tксү1/2 -340		ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub>	= 2.7 kΩ			
		2.4 V ≤ V <sub>DD</sub> < 3	3.3 V, 1.6 V ≤ V <sub>b</sub> ≤ 2.0 V,	tkcy1/2 -916		ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub>	= 5.5 kΩ			
SCKp low-level width	t <sub>KL1</sub>	4.0 V ≤ V <sub>DD</sub> ≤ 5	5.5 V, 2.7 V ≤ V <sub>b</sub> ≤ 4.0 V,	tkcy1/2 -24		ns
·		C <sub>b</sub> = 30 pF, R <sub>b</sub>	= 1.4 kΩ			
		2.7 V ≤ V <sub>DD</sub> < 4	4.0 V, 2.3 V ≤ V <sub>b</sub> ≤ 2.7 V,	tkcy1/2 -36		ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub>	,			
		· ·	3.3 V, 1.6 V ≤ V <sub>b</sub> ≤ 2.0 V,	tkcy1/2 -100		ns
		Сь = 30 pF, Rь	,			
<u> </u>						

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - **2.** p: CSI number (p = 00, 20)

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (2/3)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-spee	ed main) Mode	Unit
			MIN.	MAX.	
SIp setup time (to SCKp↑)	tsıĸı	$ 4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V}, $ $ C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega $	162		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	354		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	958		ns
SIp hold time (from SCKp↑) Note	tksi1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$	38		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	38		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	38		ns
Delay time from SCKp↓ to SOp output Note	tkso1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$		200	ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$		390	ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$		966	ns

Note When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

(Cautions and Remarks are listed on the next page.)

# (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (master mode, SCKp... internal clock output) (3/3)

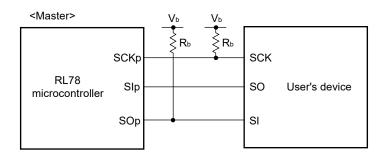
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-speed	main) Mode	Unit
			MIN.	MAX.	
SIp setup time (to SCKp↓)	tsıkı	$ 4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_{b} \leq 4.0 \text{ V}, $ $ C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega $	88		ns
			88		ns
		$ 2.4 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}, \\ C_{b} = 30 \text{ pF}, \ R_{b} = 5.5 \text{ k}\Omega $	220		ns
SIp hold time (from SCKp↓) Note	tksi1	$ 4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}, 2.7 \text{ V} \leq \text{V}_b \leq 4.0 \text{ V}, $ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega $	38		ns
			38		ns
		$ 2.4 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}, \\ C_{b} = 30 \text{ pF}, \ R_{b} = 5.5 \text{ k}\Omega $	38		ns
Delay time from SCKp↑ to SOp output Note	tkso1	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$		50	ns
		$ 2.7 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{b} \leq 2.7 \text{ V}, \\ C_{b} = 30 \text{ pF}, \ R_{b} = 2.7 \text{ k}\Omega $		50	ns
		$2.4 \text{ V} \leq \text{V}_{DD} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V},$ $C_{b} = 30 \text{ pF}, \ R_{b} = 5.5 \text{ k}\Omega$		50	ns

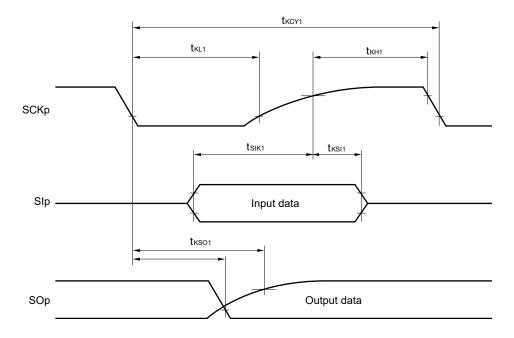
Note When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

- Cautions 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
  - 2. CSI01 and CSI11 cannot communicate at different potential.
- **Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SCKp, SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SCKp, SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage
  - 2. p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

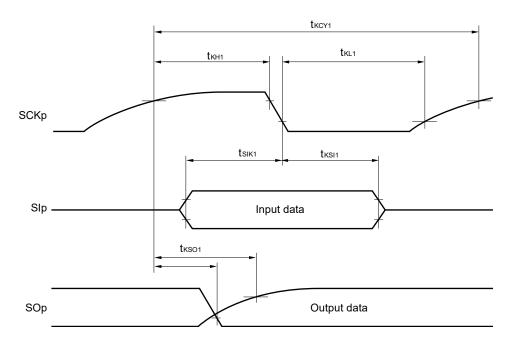
CSI mode connection diagram (during communication at different potential)



# CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)



# CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Conditions	HS (high-spe	,	Unit  ns ns ns ns ns ns ns ns ns
				MIN.	MAX.	
SCKp cycle time Note 1	tkcy2	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V,	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	24/fмск		ns
		2.7 V ≤ V <sub>b</sub> ≤ 4.0 V	8 MHz < fмск ≤ 20 MHz	20/fмск		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	16/fмск		ns
			fmck ≤ 4 MHz	12/fмск		ns
		2.7 V ≤ V <sub>DD</sub> < 4.0 V,	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	32/fмск		ns
		$2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$	16 MHz < f <sub>MCK</sub> ≤ 20 MHz	28/fмск		ns
			8 MHz < f <sub>MCK</sub> ≤ 16 MHz	24/fмск		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	16/fмск		ns
			f <sub>MCK</sub> ≤ 4 MHz	12/fмск		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V},$	20 MHz < f <sub>MCK</sub> ≤ 24 MHz	72/fmck		ns
		1.6 V ≤ V <sub>b</sub> ≤ 2.0 V	16 MHz < f <sub>MCK</sub> ≤ 20 MHz	64/fмск		ns
			8 MHz < f <sub>MCK</sub> ≤ 16 MHz	52/fмск		ns
			4 MHz < f <sub>MCK</sub> ≤ 8 MHz	32/fмск		ns
			fмcк ≤ 4 MHz	20/fмск		ns
SCKp high-/low-level	tĸн2,	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.$	7 V ≤ V <sub>b</sub> ≤ 4.0 V	tkcy2/2 - 24		ns
width	t <sub>KL2</sub>	$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.$	3 V ≤ V <sub>b</sub> ≤ 2.7 V	tkcy2/2 - 36		ns
		2.4 V ≤ V <sub>DD</sub> < 3.3 V, 1.	6 V ≤ V <sub>b</sub> ≤ 2.0 V	tkcy2/2 - 100		ns
SIp setup time	tsık2	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.$	7 V ≤ V <sub>DD</sub> ≤ 4.0 V	1/f <sub>MCK</sub> + 40		ns
(to SCKp↑) Note 2		2.7 V ≤ V <sub>DD</sub> < 4.0 V, 2.	3 V ≤ V <sub>b</sub> ≤ 2.7 V	1/f <sub>MCK</sub> + 40		ns
		2.4 V ≤ V <sub>DD</sub> < 3.3 V, 1.	6 V ≤ V <sub>DD</sub> ≤ 2.0 V	1/f <sub>MCK</sub> + 60		ns
SIp hold time (from SCKp↑) Note 3	tksı2			1/fmck + 62		ns
Delay time from SCKp↓ to	tkso2	4.0 V ≤ V <sub>DD</sub> ≤ 5.5 V, 2.	7 V ≤ V <sub>b</sub> ≤ 4.0 V,		2/fmck +	ns
SOp output Note 4		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 1.4 kg	Ω		240	
		2.7 V ≤ V <sub>DD</sub> < 4.0 V, 2.	3 V ≤ V <sub>b</sub> ≤ 2.7 V,		2/fмск +	ns
		$C_b = 30 \text{ pF}, R_b = 2.7 \text{ kg}$	Ω		428	
		2.4 V ≤ V <sub>DD</sub> < 3.3 V, 1.	$6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V},$		2/f <sub>MCK</sub> +	ns
		C <sub>b</sub> = 30 pF, R <sub>b</sub> = 5.5 ks	Ω		1146	

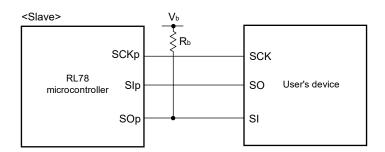
Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

- 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

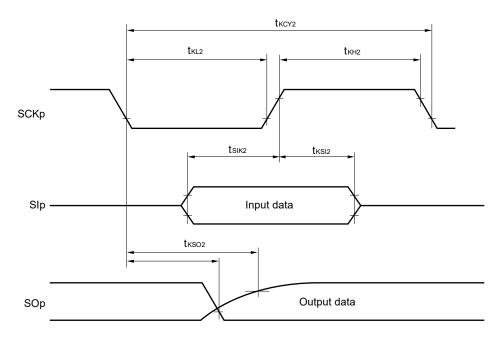
Cautions 1. Select the TTL input buffer for the SIp and SCKp pins and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

2. CSI01 and CSI11 cannot communicate at different potential.

#### CSI mode connection diagram (during communication at different potential)



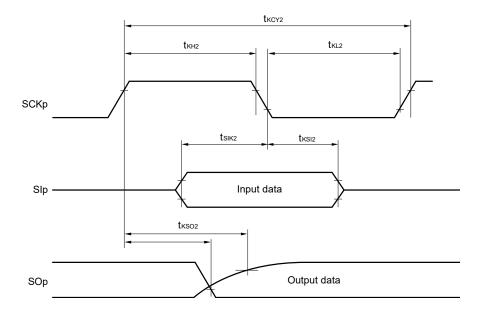
# CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



**Remarks 1.** R<sub>b</sub> [ $\Omega$ ]: Communication line (SOp) pull-up resistance, C<sub>b</sub> [F]: Communication line (SOp) load capacitance, V<sub>b</sub> [V]: Communication line voltage

- 2. p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)
- fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn))

# CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



**Remark** p: CSI number (p = 00, 20), m: Unit number (m = 0, 1), n: Channel number (n = 0)

#### (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I<sup>2</sup>C mode)

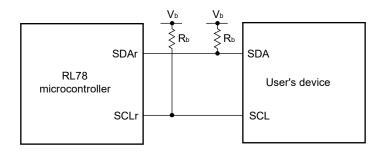
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS (high-sր Mo	-	Unit
			MIN.	MAX.	
SCLr clock frequency	fscL	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.8 \text{ k}\Omega$		100 <sup>Note1</sup>	kHz
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$		100 <sup>Note1</sup>	kHz
		2.4 V $\leq$ V <sub>DD</sub> $<$ 3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V, C <sub>b</sub> = 100 pF, R <sub>b</sub> = 5.5 k $\Omega$		100 <sup>Note1</sup>	kHz
Hold time when SCLr = "L"	tLow	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}\Omega$	4600		ns
			4600		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	4650		ns
Hold time when SCLr = "H"	tнісн	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.8 \text{ k}\Omega$	2700		ns
		$2.7 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, 2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	2400		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	1830		ns
Data setup time (reception)	tsu:dat	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}\Omega$	1/fмcк + 760 Note2		ns
			1/f <sub>MCK</sub> + 760 Note2		ns
		$2.4 \text{ V} \le \text{V}_{DD} < 3.3 \text{ V}, 1.6 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$	1/f <sub>MCK</sub> + 570 Note2		ns
Data hold time (transmission)	thd:dat	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}\Omega$	0	1420	ns
		$ 2.7 \text{ V} \leq \text{V}_{\text{DD}} < 4.0 \text{ V}, \ 2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, \ R_{\text{b}} = 2.7 \text{ k}\Omega $	0	1420	ns
		2.4 V $\leq$ V <sub>DD</sub> $<$ 3.3 V, 1.6 V $\leq$ V <sub>b</sub> $\leq$ 2.0 V, C <sub>b</sub> = 100 pF, R <sub>b</sub> = 5.5 k $\Omega$	0	1215	ns

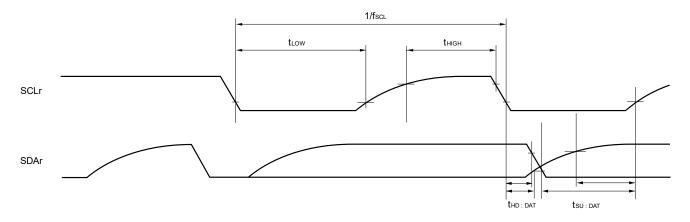
- **Notes 1.** The value must be equal to or less than fmck/4.
  - 2. Set tsu:DAT so that it will not exceed the hold time when SCLr = "L" or SCLr = "H".
- Cautions 1. Select the TTL input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the N-ch open drain output (VDD tolerance) mode for the SCLr pin by using port input mode register 1 (PIM1) and port output mode register 1 (POM1). For VH and VL, see the DC characteristics with TTL input buffer selected.
  - 2. IIC01 and IIC11 cannot communicate at different potential.

(Remarks are listed on the next page.)

#### Simplified I<sup>2</sup>C mode connection diagram (during communication at different potential)



#### Simplified I<sup>2</sup>C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** Rb [ $\Omega$ ]: Communication line (SDAr, SCLr) pull-up resistance, Cb [F]: Communication line (SDAr, SCLr) load capacitance, Vb [V]: Communication line voltage
  - 2. r: IIC Number (r = 00, 20)
  - fmck: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0,1), n: Channel number (n = 0))

#### 3.5.2 Serial interface IICA

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	HS	(high-spee	ed main) m	node	Unit
			Standa	rd Mode	Fast	Mode	
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode: fclk≥ 3.5 MHz			0	400	kHz
		Normal mode: fclk≥ 1 MHz	0	100			kHz
Setup time of restart condition	tsu:sta		4.7		0.6		μs
Hold time <sup>Note 1</sup>	thd:sta		4.0		0.6		μs
Hold time when SCLA0 = "L"	tLOW		4.7		1.3		μs
Hold time when SCLA0 = "H"	thigh		4.0		0.6		μs
Data setup time (reception)	tsu:dat		250		100		ns
Data hold time (transmission)Note 2	thd:dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto		4.0		0.6		μs
Bus-free time	<b>t</b> BUF		4.7		1.3		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

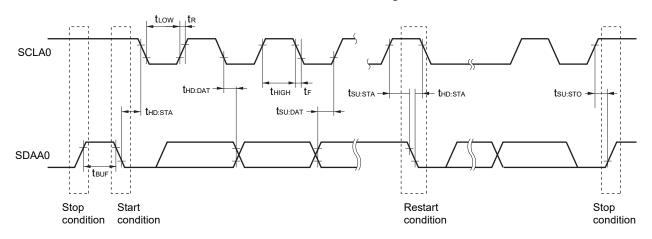
2. The maximum value (MAX.) of thd:DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Caution Only in the 30-pin products, the values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.

**Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Normal mode:  $C_b$  = 400 pF, Rb = 2.7 k $\Omega$ Fast mode:  $C_b$  = 320 pF, Rb = 1.1 k $\Omega$ 

#### **IICA** serial transfer timing



#### 3.6 Analog Characteristics

#### 3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Input channel		Reference Voltage	
	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = VDD Reference voltage (–) = Vss	Reference voltage (+) = VBGR Reference voltage (-) = AVREFM
ANI0 to ANI3	Refer to <b>3.6.1 (1)</b> .	Refer to 3.6.1 (3).	Refer to <b>3.6.1 (4)</b> .
ANI16 to ANI22	Refer to 3.6.1 (2).		
Internal reference voltage	Refer to <b>3.6.1 (1)</b> .		-
Temperature sensor output voltage			

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI2, ANI3, internal reference voltage, and temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{REFP} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$ 

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3			1.2	±3.5	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.125		39	μs
		Target pin: ANI2, ANI3	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.1875		39	μs
			2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs
		10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.375		39	μs
		Target pin: Internal reference voltage, and	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.5625		39	μs
		temperature sensor output voltage (HS (high-speed main) mode)	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.25	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.25	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±2.5	LSB
Differential linearity error	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±1.5	LSB
Analog input voltage	VAIN	ANI2, ANI3		0		AVREFP	V
		Internal reference voltage (HS (high-speed main) m	V <sub>BGR</sub> Note 4			V	
		Temperature sensor output voltage (HS (high-speed main) mode)		V <sub>TMPS25</sub> Note 4			V

(Notes are listed on the next page.)

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - **3.** When  $AV_{REFP} < V_{DD}$ , the MAX. values are as follows.

Overall error: Add  $\pm 1.0$  LSB to the MAX. value when AV<sub>REFP</sub> =  $V_{DD}$ .

Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ±0.5 LSB to the MAX. value when AVREFP = VDD.

4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

### (2) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI22

(T<sub>A</sub> = -40 to +105°C, 2.4 V ≤ AV<sub>REFP</sub> ≤ V<sub>DD</sub> ≤ 5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = AV<sub>REFP</sub>, Reference voltage (-) =  $AV_{REFM} = 0 V$ 

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error Note 1	AINL	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3			1.2	±5.0	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.125		39	μs
		Target ANI pin: ANI16 to ANI22	2.7 V ≤ VDD ≤ 5.5 V	3.1875		39	μs
		2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs	
Zero-scale error Notes 1, 2	EZS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3			±0.35	%FSR	
Full-scale error Notes 1, 2	EFS	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±0.35	%FSR
Integral linearity error Note 1	ILE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±3.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution AV <sub>REFP</sub> = V <sub>DD</sub> Note 3				±2.0	LSB
Analog input voltage	VAIN	ANI16 to ANI22		0		AVREFP and VDD	V

#### Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When  $AV_{REFP} \le V_{DD}$ , the MAX. values are as follows.

Overall error: Add ±4.0 LSB to the MAX. value when AVREFP = VDD.

Zero-scale error/Full-scale error: Add ±0.20%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AVREFP = VDD.

(3) When reference voltage (+) = V<sub>DD</sub> (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V<sub>SS</sub> (ADREFM = 0), target pin: ANI0 to ANI3, ANI16 to ANI22, internal reference voltage, and temperature sensor output voltage

(T<sub>A</sub> = -40 to +105°C, 2.4 V ≤ V<sub>DD</sub> ≤ 5.5 V, V<sub>SS</sub> = 0 V, Reference voltage (+) = V<sub>DD</sub>, Reference voltage (-) = V<sub>SS</sub>)

Parameter	Symbol	Condition	ns	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		10	bit
Overall error <sup>Note 1</sup>	AINL	10-bit resolution			1.2	±7.0	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ VDD ≤ 5.5 V	2.125		39	μs
		Target pin: ANI0 to ANI3, ANI16 to ANI22	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.1875		39	μs
		ANI16 to ANI22	2.4 V ≤ V <sub>DD</sub> ≤ 5.5 V	17		39	μs
Conversion time	tconv	10-bit resolution	3.6 V ≤ V <sub>DD</sub> ≤ 5.5 V	2.375		39	μs
		Target pin: internal reference	2.7 V ≤ V <sub>DD</sub> ≤ 5.5 V	3.5625		39	μs
		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	2.4 V ≤ VDD ≤ 5.5 V	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	10-bit resolution	<u> </u>			±0.60	%FSR
Full-scale error <sup>Notes 1, 2</sup>	EFS	10-bit resolution				±0.60	%FSR
Integral linearity errorNote 1	ILE	10-bit resolution				±4.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution				±2.0	LSB
Analog input voltage	Vain	ANI0 to ANI3, ANI16 to ANI2	2	0		V <sub>DD</sub>	V
		Internal reference voltage (HS (high-speed main) mode)		V <sub>BGR</sub> Note 3			V
		Temperature sensor output voltage (HS (high-speed main) mode)		V <sub>TMPS25</sub> Note 3			V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM (ADREFM = 1), target pin: ANI0, ANI2, ANI3, and ANI16 to ANI22

(TA = -40 to +105°C, 2.4 V  $\leq$  VDD  $\leq$  5.5 V, Vss = 0 V, Reference voltage (+) = VBGR Note 3, Reference voltage (-) = AVREFM Note 4 = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res			8		bit
Conversion time	tconv	8-bit resolution	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	EZS	8-bit resolution			±0.60	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	8-bit resolution			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution			±1.0	LSB
Analog input voltage	Vain		0		V <sub>BGR</sub> Note 3	V

- Notes 1. Excludes quantization error (±1/2 LSB).
  - 2. This value is indicated as a ratio (%FSR) to the full-scale value.
  - 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.
  - 4. When reference voltage (–) = Vss, the MAX. values are as follows.
    Zero-scale error: Add ±0.35%FSR to the MAX. value when reference voltage (–) = AVREFM.
    Integral linearity error: Add ±0.5 LSB to the MAX. value when reference voltage (–) = AVREFM.
    Differential linearity error: Add ±0.2 LSB to the MAX. value when reference voltage (–) = AVREFM.

#### 3.6.2 Temperature sensor/internal reference voltage characteristics

(T<sub>A</sub> = -40 to +105°C, 2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V, V<sub>SS</sub> = 0 V, HS (high-speed main) mode

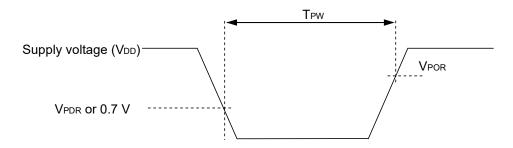
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	V <sub>TMPS25</sub>	Setting ADS register = 80H, TA = +25°C		1.05		V
Internal reference voltage	V <sub>BGR</sub>	Setting ADS register = 81H	1.38	1.45	1.50	V
Temperature coefficient	Fvтмps	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

#### 3.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	Vpor	Power supply rise time	1.45	1.51	1.57	V
	VPDR	Power supply fall time	1.44	1.50	1.56	V
Minimum pulse width Note	T <sub>PW</sub>		300			μs

Note Minimum time required for a POR reset when  $V_{DD}$  exceeds below  $V_{PDR}$ . This is also the minimum time required for a POR reset from when  $V_{DD}$  exceeds below 0.7 V to when  $V_{DD}$  exceeds  $V_{POR}$  while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



### 3.6.4 LVD circuit characteristics

#### LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection supply voltage	V <sub>LVD0</sub>	Power supply rise time	3.90	4.06	4.22	V
		Power supply fall time	3.83	3.98	4.13	V
	V <sub>LVD1</sub>	Power supply rise time	3.60	3.75	3.90	V
		Power supply fall time	3.53	3.67	3.81	V
	V <sub>LVD2</sub>	Power supply rise time	3.01	3.13	3.25	V
		Power supply fall time	2.94	3.06	3.18	V
	V <sub>LVD3</sub>	Power supply rise time	2.90	3.02	3.14	V
		Power supply fall time	2.85	2.96	3.07	V
	V <sub>LVD4</sub>	Power supply rise time	2.81	2.92	3.03	V
		Power supply fall time	2.75	2.86	2.97	V
	V <sub>LVD5</sub>	Power supply rise time	2.70	2.81	2.92	>
		Power supply fall time	2.64	2.75	2.86	V
	V <sub>LVD6</sub>	Power supply rise time	2.61	2.71	2.81	V
		Power supply fall time	2.55	2.65	2.75	V
	V <sub>LVD7</sub>	Power supply rise time	2.51	2.61	2.71	V
		Power supply fall time	2.45	2.55	2.65	V
Minimum pulse width	tıw		300			μs
Detection delay time					300	μs

#### LVD detection voltage of interrupt & reset mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol		Cond	MIN.	TYP.	MAX.	Unit	
Interrupt and reset	V <sub>LVDD0</sub>	VPOC2,	VPOC1, VPOC1 = 0, 1, 1, falli	ng reset voltage	2.64	2.75	2.86	V
mode	V <sub>LVDD1</sub>		LVIS1, LVIS0 = 1, 0	Rising reset release voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	V
	V <sub>LVDD2</sub>		LVIS1, LVIS0 = 0, 1	Rising reset release voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V
	V <sub>LVDD3</sub>		LVIS1, LVIS0 = 0, 0	Rising reset release voltage	3.90	4.06	4.22	V
				Falling interrupt voltage	3.83	3.98	4.13	V

#### 3.6.5 Power supply voltage rising slope characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

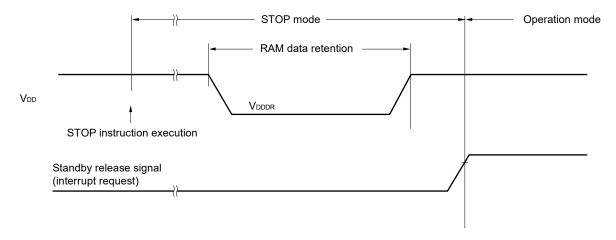
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V<sub>DD</sub> reaches the operating voltage range shown in 3.4 AC Characteristics.

#### 3.7 RAM Data Retention Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 Note		5.5	V

**Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



#### 3.8 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$ 

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk		1		24	MHz
Code flash memory rewritable times Notes 1, 2, 3	Cerwr	Retained for 20 years  TA = 85°C Note 4	1,000			Times
Data flash memory rewritable times Notes 1, 2, 3		Retained for 1 year  TA = 25°C		1,000,000		
		Retained for 5 years  TA = 85°C Note 4	100,000			
		Retained for 20 years  TA = 85°C Note 4	10,000			

- **Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.
  - 2. When using flash memory programmer and Renesas Electronics self programming library
  - **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
  - 4. This temperature is the average value at which data are retained.

#### 3.9 Dedicated Flash Memory Programmer Communication (UART)

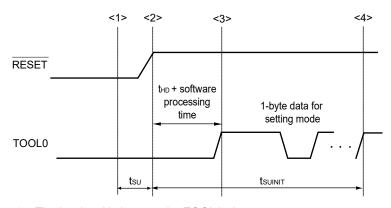
#### $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate Dur		During serial programming	115,200		1,000,000	bps

#### 3.10 Timing of Entry to Flash Memory Programming Modes

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$ 

(1A40 to · 100 0, 2.4 v = v 00 = 0.0 v, v	00 0 1		,			
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset are released before external release			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	<b>t</b> su	POR and LVD reset are released before external release	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released	tно	POR and LVD reset are released before external release	1			ms
(excluding the processing time of the firmware to control the flash memory)						



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.

tsu: Time to release the external reset after the TOOL0 pin is set to the low level

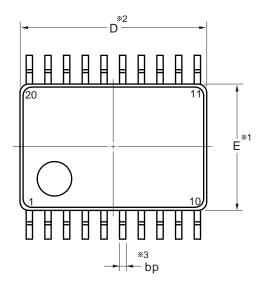
thd: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

### 4. PACKAGE DRAWINGS

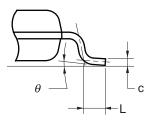
#### 4.1 20-pin products

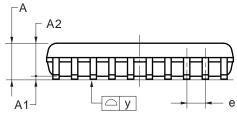
R5F1026AASP, R5F10269ASP, R5F10268ASP, R5F10267ASP, R5F10266ASP R5F1036AASP, R5F10369ASP, R5F10368ASP, R5F10367ASP, R5F10366ASP R5F1026ADSP, R5F10269DSP, R5F10268DSP, R5F10267DSP, R5F10366DSP R5F1036ADSP, R5F10369DSP, R5F10368DSP, R5F10367DSP, R5F10266GSP R5F1026AGSP, R5F10269GSP, R5F10268GSP, R5F10267GSP, R5F10266GSP

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]	
P-LSSOP20-4.4x6.5-0.65	PLSP0020JB-A	P20MA-65-NAA-1	0.1	



detail of lead end







#### NOTE

- 1.Dimensions "%1" and "%2" do not include mold flash.
- 2.Dimension "X3" does not include trim offset.

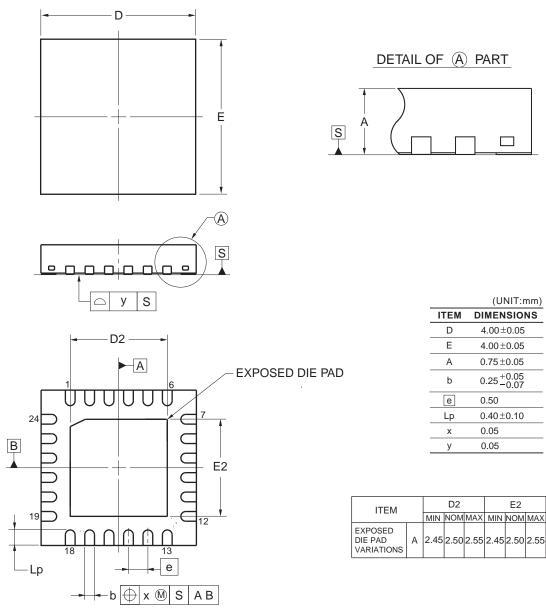
	(UNIT:mm)
ITEM	DIMENSIONS
D	6.50±0.10
Е	4.40±0.10
HE	6.40±0.20
Α	1.45 MAX.
A1	0.10±0.10
A2	1.15
е	0.65±0.12
bp	$0.22 + 0.10 \\ -0.05$
С	$0.15 \pm 0.05 \\ -0.02$
L	0.50±0.20
У	0.10
θ	0° to 10°

 $\bigcirc$  2012 Renesas Electronics Corporation. All rights reserved.

#### 4.2 24-pin products

R5F1027AANA, R5F10279ANA, R5F10278ANA, R5F10277ANA R5F1037AANA, R5F10379ANA, R5F10378ANA, R5F10377ANA R5F1027ADNA, R5F10279DNA, R5F10278DNA, R5F10277DNA R5F1037ADNA, R5F10379DNA, R5F10378DNA, R5F10377DNA R5F1027AGNA, R5F10279GNA, R5F10278GNA, R5F10277GNA

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-HWQFN24-4x4-0.50	PWQN0024KE-A	P24K8-50-CAB-1	0.04

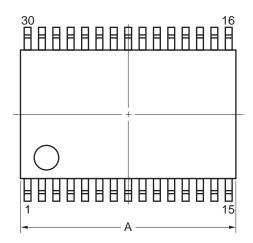


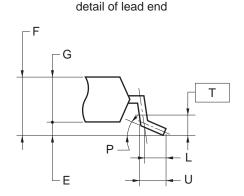
©2012 Renesas Electronics Corporation. All rights reserved.

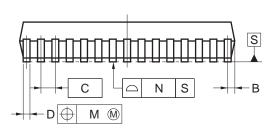
#### 4.3 30-pin products

R5F102AAASP, R5F102A9ASP, R5F102A8ASP, R5F102A7ASP R5F103AAASP, R5F103A9ASP, R5F103A8ASP, R5F103A7ASP R5F102AADSP, R5F102A9DSP, R5F102A8DSP, R5F102A7DSP R5F103AADSP, R5F103A9DSP, R5F103A8DSP, R5F103A7DSP R5F102AAGSP, R5F102A9GSP, R5F102A8GSP, R5F102A7GSP

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LSSOP30-0300-0.65	PLSP0030JB-B	S30MC-65-5A4-3	0.18

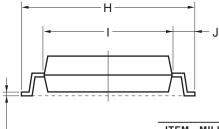






### NOTE

Each lead centerline is located within 0.13 mm of its true position (T.P.) at maximum material condition.



ITEM	MILLIMETERS
A	9.85±0.15
В	0.45 MAX.
С	0.65 (T.P.)
D	$0.24^{+0.08}_{-0.07}$
Е	0.1±0.05
F	1.3±0.1
G	1.2
Н	8.1±0.2
I	6.1±0.2
J	1.0±0.2
K	0.17±0.03
L	0.5
М	0.13
N	0.10
Р	3°+5°
Т	0.25
U	0.6±0.15

©2012 Renesas Electronics Corporation. All rights reserved.

### RL78/G12 Datasheet

		Description		
Rev.	Date	Page	Summary	
1.00	Dec 10, 2012	-	First Edition issued	
2.00	Sep 06, 2013	1	Modification of 1.1 Features	
		3	Modification of 1.2 List of Part Numbers	
		4	Modification of Table 1-1. List of Ordering Part Numbers, Note, and Caution	
		7 to 9	Modification of package name in 1.4.1 to 1.4.3	
		14	Modification of tables in 1.7 Outline of Functions	
		17	Modification of description of table in 2.1 Absolute Maximum Ratings (T <sub>A</sub> = 25°C)	
		18	Modification of table, Note, and Caution in 2.2.1 X1 oscillator characteristics	
		18	Modification of table in 2.2.2 On-chip oscillator characteristics	
		19	Modification of Note 3 in 2.3.1 Pin characteristics (1/4)	
		20	Modification of Note 3 in 2.3.1 Pin characteristics (2/4)	
		23	Modification of Notes 1 and 2 in (1) 20-, 24-pin products (1/2)	
		24	Modification of Notes 1 and 3 in (1) 20-, 24-pin products (2/2)	
		25	Modification of Notes 1 and 2 in (2) 30-pin products (1/2)	
		26	Modification of Notes 1 and 3 in (2) 30-pin products (2/2)	
		27	Modification of (3) Peripheral functions (Common to all products)	
		28	Modification of table in 2.4 AC Characteristics	
		29	Addition of Minimum Instruction Execution Time during Main System Clock Operation	
		30	Modification of figures of AC Timing Test Point and External Main System Clock Timing	
		31	Modification of figure of AC Timing Test Point	
		31	Modification of description and Note 2 in (1) During communication at same potential (UART mode)	
		32	Modification of description in (2) During communication at same potential (CSI mode)	
		33	Modification of description in (3) During communication at same potential (CSI mode)	
		34	Modification of description in (4) During communication at same potential (CSI mode)	
		36	Modification of table and Note 2 in (5) During communication at same potential (simplified I <sup>2</sup> C mode)	
		38, 39	Modification of table and Notes 1 to 9 in (6) Communication at different potential	
			(1.8 V, 2.5 V, 3 V) (UART mode)	
		40	Modification of Remarks 1 to 3 in (6) Communication at different potential (1.8 V,	
		41	2.5 V, 3 V) (UART mode)  Modification of table in (7) Communication at different potential (2.5 V, 3 V) (CSI	
		42	mode)  Modification of Caution in (7) Communication at different potential (2.5 V, 3 V) (CSI mode)	
		43	Modification of table in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/3)	
		44	Modification of table and Notes 1 and 2 in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/3)	
		45	Modification of table, Note 1, and Caution 1 in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (3/3)	
		47	Modification of table in (9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode)	
		50	Modification of table, Note 1, and Caution 1 in (10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I <sup>2</sup> C mode)	

		Description		
Rev.	Date	Page	Summary	
2.00	Sep 06, 2013	52	Modification of Remark in 2.5.2 Serial interface IICA	
		53	Addition of table to 2.6.1 A/D converter characteristics	
		53	Modification of description in 2.6.1 (1)	
		54	Modification of Notes 3 to 5 in 2.6.1 (1)	
		54	Modification of description and Notes 2 to 4 in 2.6.1 (2)	
2.00	Sep 06, 2013	55	Modification of description and Notes 3 and 4 in 2.6.1 (3)	
		56	Modification of description and Notes 3 and 4 in 2.6.1 (4)	
		57	Modification of table in 2.6.2 Temperature sensor/internal reference voltage characteristics	
		57	Modification of table and Note in 2.6.3 POR circuit characteristics	
		58	Modification of table in 2.6.4 LVD circuit characteristics	
		59	Modification of table of LVD detection voltage of interrupt & reset mode	
		59	Modification of number and title to 2.6.5 Power supply voltage rising slope characteristics	
		61	Modification of table, figure, and Remark in 2.10 Timing of Entry to Flash Memory Programming Modes	
		62 to 103	Addition of products of industrial applications (G: T <sub>A</sub> = -40 to +105°C)	
		104 to 106	Addition of products of industrial applications (G: T <sub>A</sub> = -40 to +105°C)	
2.10	Mar 25, 2016	6	Modification of Figure 1-1 Part Number, Memory Size, and Package of RL78/G12	
		7	Modification of Table 1-1 List of Ordering Part Numbers	
		8	Addition of product name (RL78/G12) and description (Top View) in 1.4.1 20-pin products	
		9	Addition of product name (RL78/G12) and description (Top View) in 1.4.2 24-pin products	
		10	Addition of product name (RL78/G12) and description (Top View) in 1.4.3 30-pin products	
		15	Modification of description in 1.7 Outline of Functions	
		16	Modification of description, and addition of target products	
		52	Modification of note 2 in 2.5.2 Serial interface IICA	
		60	Modification of title and note, and addition of caution in 2.7 RAM Data Retention Characteristics	
		60	Modification of conditions in 2.8 Flash Memory Programming Characteristics	
		62	Modification of description, and addition of target products and remark	
		94	Modification of note 2 in 3.5.2 Serial interface IICA	
		102	Modification of title and note in 3.7 RAM Data Retention Characteristics	
		102	Modification of conditions in 3.8 Flash Memory Programming Characteristics	
		104 to 106	Addition of package name	
2.20	Oct 31, 2018	4	Modification of Table 1-1 List of Ordering Part Numbers	
		7	Modification of pin configuration diagram in 1.4.1 20-pin products	

All trademarks and registered trademarks are the property of their respective owners.

SuperFlash is a registered trademark of Silicon Storage Technology, Inc. in several countries including the United States and Japan.

Caution: This product uses SuperFlash® technology licensed from Silicon Storage Technology, Inc.

#### NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE: Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

#### Notice

- criptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products and application examples. You are fully resp the incorporation or any other use of the circuits, software, and information in the design of your product or system. Renesas Electronics disclaims any and all liability for any losses and damages incurred by you or third parties arising from the use of these circuits, software, or information
- 2. Renesas Electronics hereby expressly disclaims any warranties against and liability for infringement or any other claims involving patents, copyrights, or other intellectual property rights of third parties, by or arising from the use of Renesas Electronics products or technical information described in this document, including but not limited to, the product data, drawings, charts, programs, algorithms, and application
- 3. No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
- 4. You shall not alter, modify, copy, or reverse engineer any Renesas Electronics product, whether in whole or in part. Renesas Electronics disclaims any and all liability for any losses or damages incurred by you or third parties arising from such alteration, modification, copying or reverse engineering.
- 5. Renesas Electronics products are classified according to the following two quality grades: "Standard" and "High Quality". The intended applications for each Renesas Electronics product depends on the product's quality grade, as indicated below.
  - Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment: industrial robots: etc.

"High Quality": Transportation equipment (automobiles, trains, ships, etc.); traffic control (traffic lights); large-scale communication equipment; key financial terminal systems; safety control equipment; etc. Unless expressly designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not intended or authorized for use in products or systems that may pose a direct threat to human life or bodily injury (artificial life support devices or systems; surgical implantations; etc.), or may cause serious property damage (space system; undersea repeaters; nuclear power control systems; aircraft control systems; key plant systems; military equipment; etc.). Renesas Electronics disclaims any and all liability for any damages or losses incurred by you or any third parties arising from the use of any Renesas Electronics product that is inconsistent with any Renesas Electronics data sheet, user's manual or other Renesas Electronics document.

- 6. When using Renesas Electronics products, refer to the latest product information (data sheets, user's manuals, application notes, "General Notes for Handling and Using Semiconductor Devices" in the reliability handbook, etc.), and ensure that usage conditions are within the ranges specified by Renesas Electronics with respect to maximum ratings, operating power supply voltage range, heat dissipation characteristics, installation, etc. Renesas Electronics disclaims any and all liability for any malfunctions, failure or accident arising out of the use of Renesas Electronics products outside of such specified
- 7. Although Renesas Electronics endeavors to improve the quality and reliability of Renesas Electronics products, semiconductor products have specific characteristics, such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Unless designated as a high reliability product or a product for harsh environments in a Renesas Electronics data sheet or other Renesas Electronics document, Renesas Electronics products are not subject to radiation resistance design. You are responsible for implementing safety measures to guard against the possibility of bodily injury, injury or damage caused by fire, and/or danger to the public in the event of a failure or malfunction of Renesas Electronics products, such as safety design for hardware and software, including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult and impractical, you are responsible for evaluating the safety of the final products or systems manufactured by you.
- 8. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. You are responsible for carefully and sufficiently investigating applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive, and using Renesas Electronics products in compliance with all these applicable laws and regulations. Renesas Electronics disclaims any and all liability for damages or losses occurring as a result of your noncompliance with applicable aws and regulations
- 9. Renesas Electronics products and technologies shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations. You shall comply with any applicable export control laws and regulations promulgated and administered by the governments of any countries asserting jurisdiction over the parties or transactions.
- 10. It is the responsibility of the buyer or distributor of Renesas Electronics products, or any other party who distributes, disposes of, or otherwise sells or transfers the product to a third party, to notify such third earty in advance of the contents and conditions set forth in this document
- 11. This document shall not be reprinted, reproduced or duplicated in any form, in whole or in part, without prior written consent of Renesas Electronics
- 12. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products
- (Note 1) "Renesas Electronics" as used in this document means Renesas Electronics Corporation and also includes its directly or indirectly controlled subsidiaries.

(Note 2) "Renesas Electronics product(s)" means any product developed or manufactured by or for Renesas Electronics

(Rev.4.0-1 November 2017)



#### SALES OFFICES

#### Renesas Electronics Corporation

http://www.renesas.com

Refer to "http://www.renesas.com/" for the latest and detailed information.

Renesas Electronics Corporation TOYOSU FORESIA, 3-2-24 Toyosu, Koto-ku, Tokyo 135-0061, Japan

Renesas Electronics America Inc. 1001 Murphy Ranch Road, Milpitas, CA 95035, U.S.A. Tel: +1-408-432-8888, Fax: +1-408-434-5351

Renesas Electronics Canada Limited 9251 Yonge Street, Suite 8309 Richmond Hill, Ontario Canada L4C 9T3 Tel: +1-905-237-2004

Renesas Electronics Europe Limited
Dukes Meadow, Millboard Road, Bourne End, Buckinghamshire, SL8 5FH, U.K
Tel: +44-1628-651-700

Renesas Electronics Europe GmbH

Arcadiastrasse 10, 40472 Düsseldorf, Germany Tel: +49-211-6503-0, Fax: +49-211-6503-1327

Renesas Electronics (China) Co., Ltd.
Room 1709 Quantum Plaza, No.27 ZhichunLu, Haidian District, Beijing, 100191 P. R. China Tel: +86-10-8235-1155, Fax: +86-10-8235-7679

Renesas Electronics (Shanghai) Co., Ltd.

Unit 301, Tower A, Central Towers, 555 Langae Road, Putuo District, Shanghai, 200333 P. R. China Tel: +86-21-2226-0888, Fax: +86-21-2226-0999

Renesas Electronics Hong Kong Limited

Unit 1601-1611, 16IF., Tower 2, Grand Century Place, 193 Prince Edward Road West, Mongkok, Kowloon, Hong Kong Tel: +852-2265-6688, Fax: +852 2886-9022

Renesas Electronics Taiwan Co., Ltd. 13F, No. 363, Fu Shing North Road, Taipei 10543, Taiwan Tel: +886-2-8175-9600, Fax: +886 2-8175-9670

Renesas Electronics Singapore Pte. Ltd.
80 Bendemeer Road, Unit #06-02 Hyflux Innovation Centre, Singapore 339949
Tel: +65-6213-0200, Fax: +65-6213-0300

Renesas Electronics Malaysia Sdn.Bhd.
Unit 1207, Block B, Menara Amcorp, Amcorp Trade Centre, No. 18, Jln Persiaran Barat, 46050 Petaling Jaya, Selangor Darul Ehsan, Malaysia Tel: +60-3-7955-9390, Fax: +60-3-7955-9510

Renesas Electronics India Pvt. Ltd. No.777C, 100 Feet Road, HAL 2nd Stage, Ind Tel: +91-80-67208700, Fax: +91-80-67208777 Indiranagar, Bangalore 560 038, India

Renesas Electronics Korea Co., Ltd. 17F, KAMCO Yangjae Tower, 262, Gangnam-daero, Gangnam-gu, Seoul, 06265 Korea Tel: +82-2-558-3737, Fax: +82-2-558-5338